

Chapter 20

Degradation Modeling and Destructive Degradation Data Analysis

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Based on [Meeker, Escobar, and Pascual \(2021\)](#): *Statistical Methods for Reliability Data, Second Edition*, John Wiley & Sons Inc.

May 24, 2021
11h 6min

Chapter 20

Accelerated Destructive Degradation Tests Data, Models, and Data Analysis

Objectives and Overview

Topics discussed in this chapter are:

- Degradation data and degradation path models.
- Mechanistic motivation for degradation path models and parameter interpretation.
- **Destructive** degradation background and an example of destructive degradation field data analysis.
- Failure-time distributions induced from degradation models and failure-time inferences.
- Background and an example of **accelerated** destructive degradation testing (ADDT) and model building.
- Fitting an acceleration model to ADDT data.
- ADDT model checking.
- ADDT failure-time inferences.
- ADDT using an asymptotic model.

Chapter 20

Degradation Modeling and Destructive Degradation Data Analysis

Segment 1

Degradation Reliability Data and Degradation Path Models Introduction and Background

Degradation Leading to Failure

- Most failures can be traced to an underlying degradation process.
- Degradation curves can have different shapes.
- A **soft failure** occurs when the observed degradation level crosses a threshold.
- Some applications have more than one degradation variable or more than one underlying degradation process.
- Examples here have only one degradation variable and underlying degradation process.

Degradation Data

- Degradation is natural response for some reliability applications.
- Degradation data can provide considerably more reliability information than censored failure-time data (especially with few or no failures). Reduction of degradation data to failure-time data loses information.
- There can be useful reliability inferences even with 0 failures.
- Direct observation of the degradation process allows direct modeling of the failure-causing mechanism.
- Degradation data provides better justification and credibility for extrapolative acceleration models. (Modeling is closer to the physics-of-failure.)

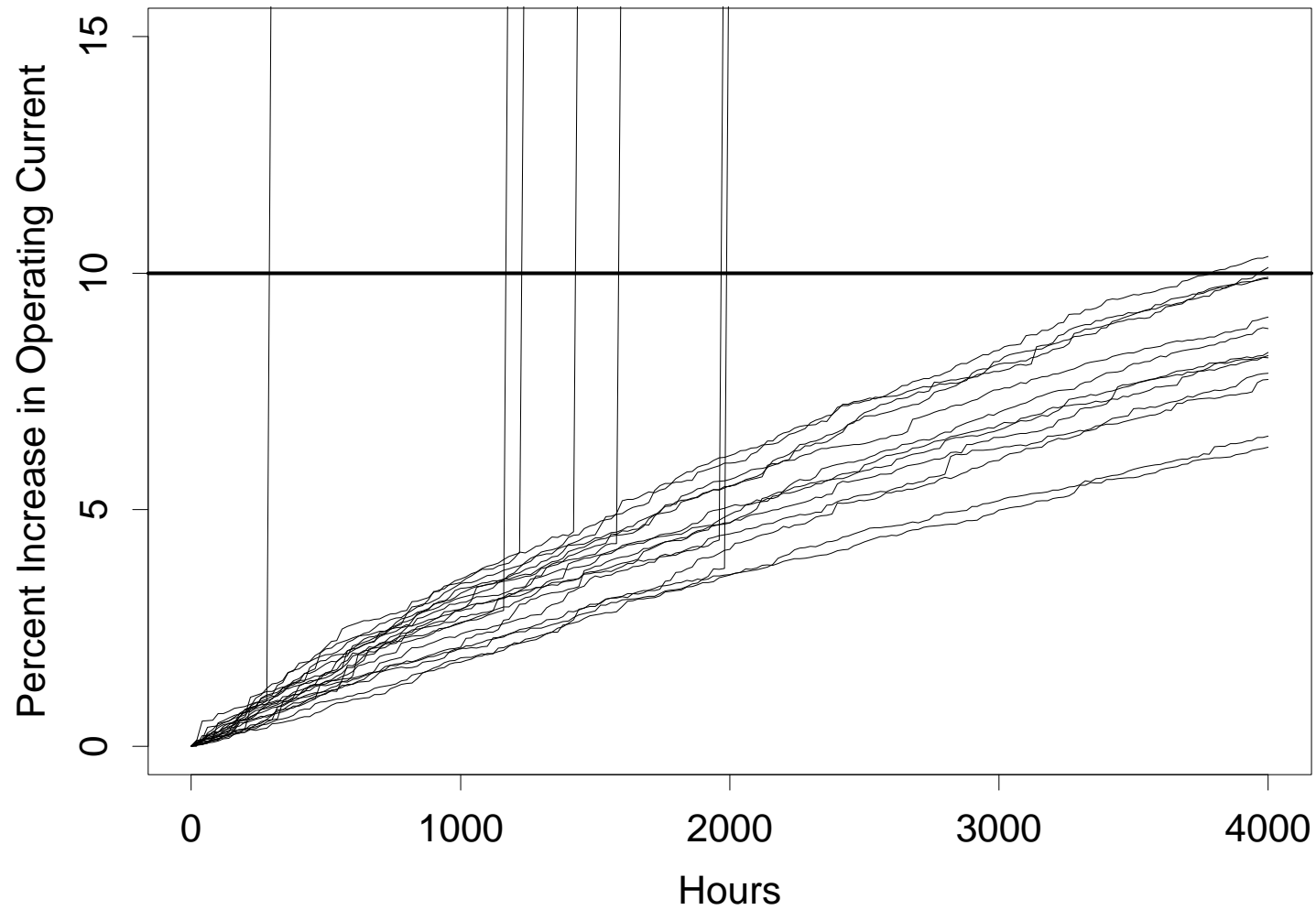
Limitations of Degradation Data

- Degradation data may be difficult or impossible to obtain.
- Obtaining degradation data may have an effect on future product degradation (e.g., taking apart a motor to measure wear).
- Substantial measurement error can diminish the information in degradation data.
- In some applications the **degradation** level may not correlate well with failure.

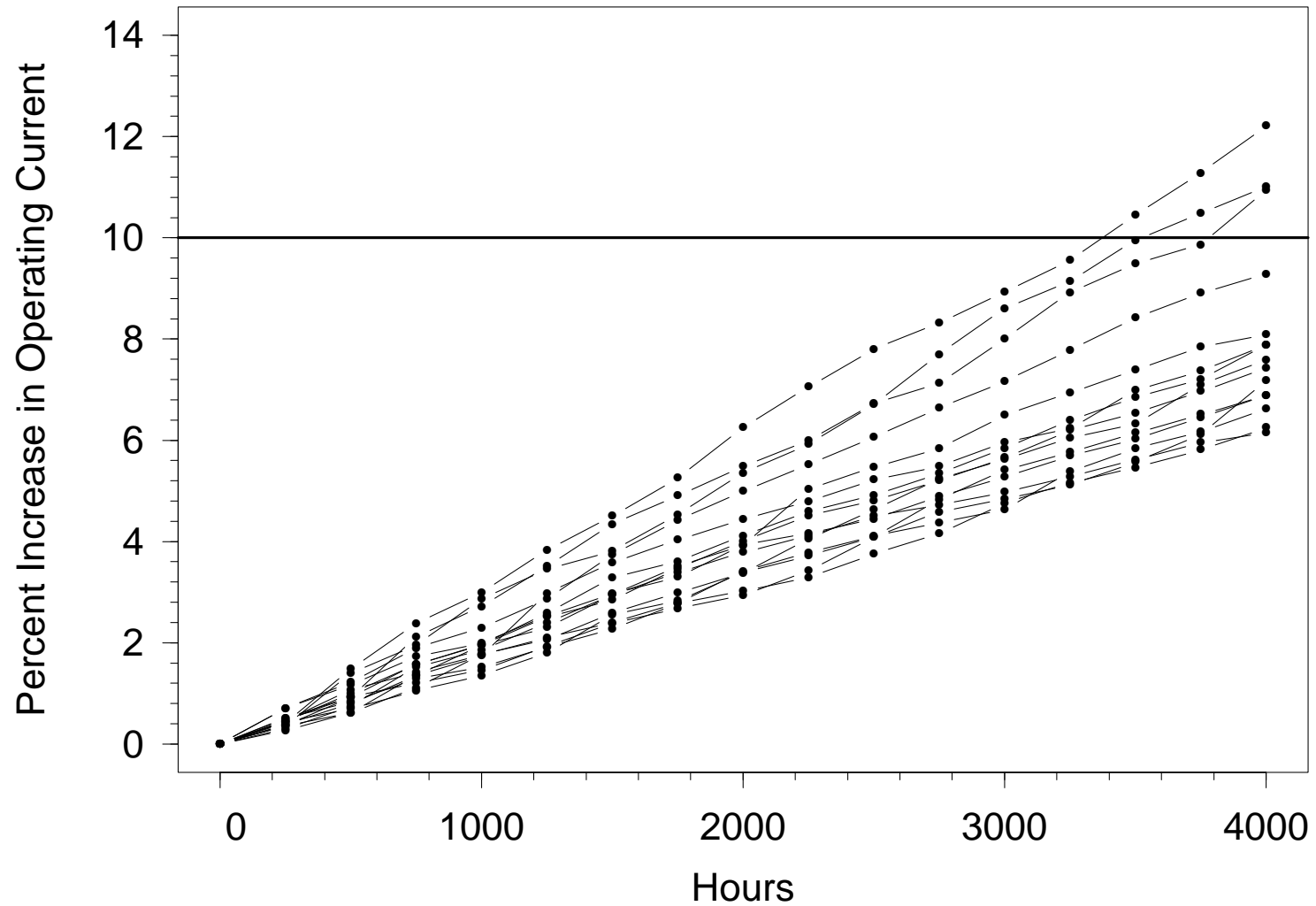
Types of Degradation Data

- Destructive degradation data (Chapter [20](#)).
- Repeated-measures degradation data (Chapter [21](#)).
- The underlying paths models will be the same for both types of data.
- In models for repeated measures degradation data, one or more of the parameters in assumed paths model will typically have random-parameter unit-to-unit variability.

Percent Increase in Operating Current for GaAs Lasers Tested at 80°C



Plot of Laser Operating Current as a Function of Time



Laser Repeated Measures Degradation Data

- Percentage increase in operating current for GaAs lasers tested at 80°C.
- Fifteen (15) devices each measured every 250 hours up to 4000 hours of operation.
- For these devices and the corresponding application, a $\mathcal{D}_f = 10\%$ increase in current was the specified failure level.

General Degradation Path Models

- When there are no explanatory variables, the general degradation path models has the form

$$Y = h_d[\mathcal{D}(t)] = \xi(t) + \epsilon.$$

- Transformations are often used to linearize or otherwise simplify the form of a degradation model and may be suggested by physics of failure or from the data.
- $h_d[\mathcal{D}(t)]$ is a monotone increasing transformation of the observed degradation $\mathcal{D}(t)$.
- $\xi(t)$ is a monotone function (either increasing or decreasing) of (possibly transformed) time $\tau = h_t(t)$.
- The error term ϵ will be described by a location-scale distribution (e.g., a normal distribution) with parameters ($\mu = 0$ and σ_ϵ (although technically, other distributions could also be used)).

General Degradation Path Regression Models

- Explanatory variables x arise from
 - ▶ Accelerating variables (e.g., temperature, voltage, or pressure) in accelerated tests.
 - ▶ Covariates from field data.

The regression model for degradation will be

$$Y = h_d[\mathcal{D}(t)] = \xi(t, x) + \epsilon.$$

- For a fixed value of x , $\xi(t, x)$ is a monotone increasing function of (possibly transformed) time $\tau = h_t(t)$.
- The transformation for the x could be suggested from physics of failure (e.g., the Arrhenius and Power-rule models described in Chapters 18 and 19) or from the data.

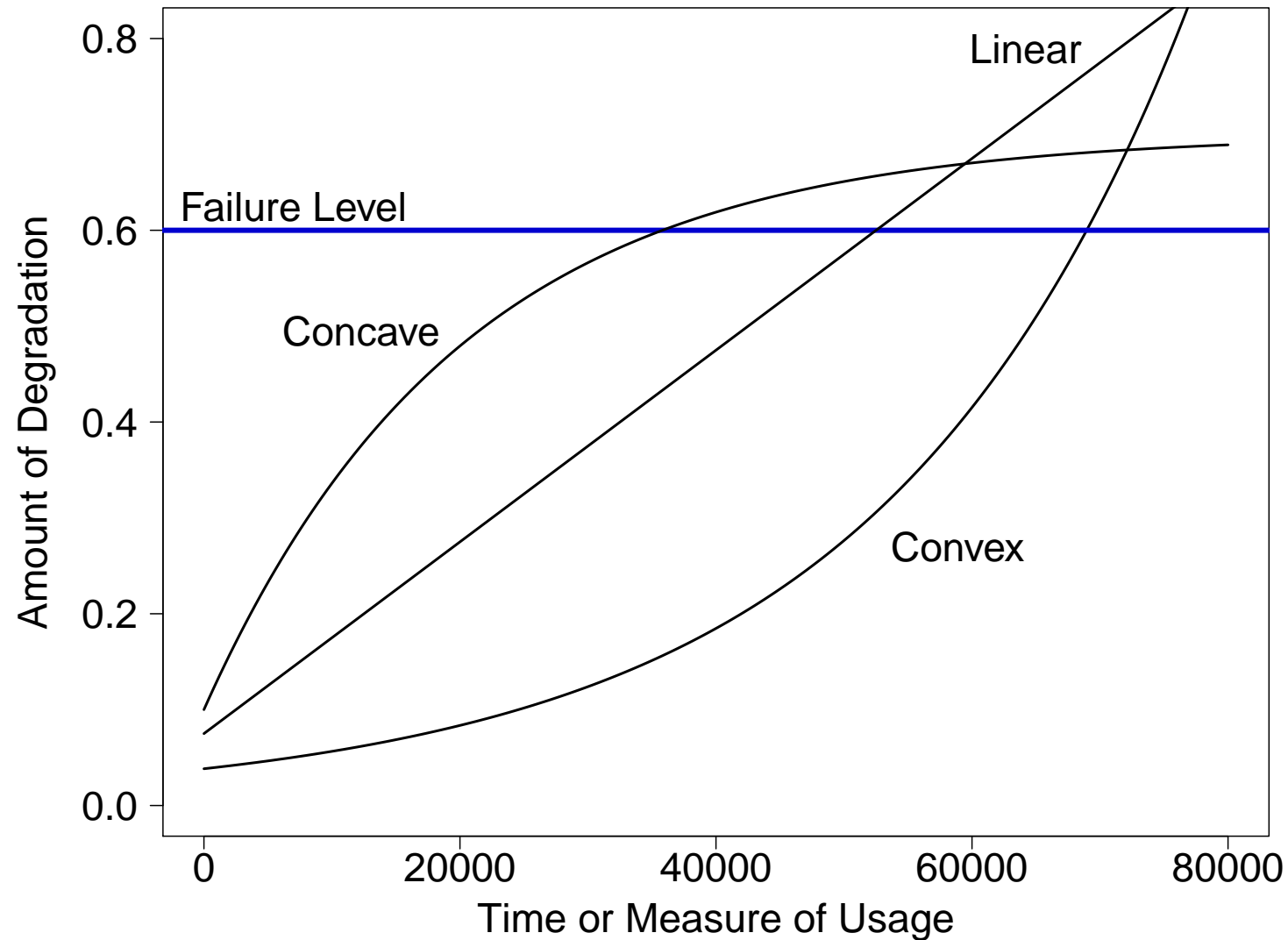
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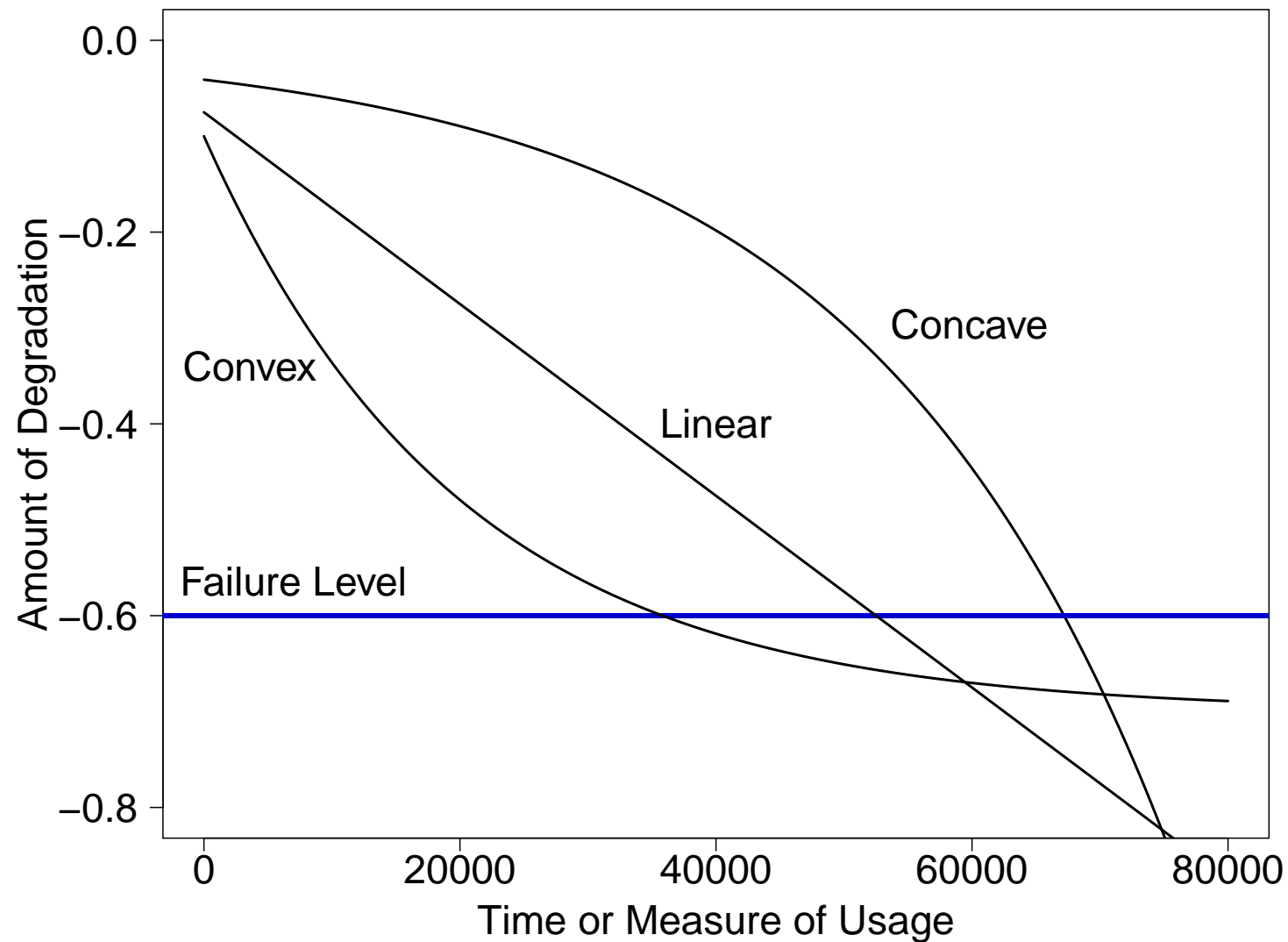
Segment 2

Mechanistic Motivation for Degradation Path Models and Parameter Interpretation

Possible Shapes for Univariate Increasing Degradation Curves



Possible Shapes for Univariate Decreasing Degradation Curves



Possible Shapes for Univariate Degradation Curves

- **Linear degradation:** Degradation **rate**

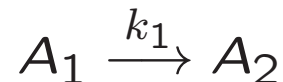
$$\frac{d\xi(t)}{dt} = \beta_1$$

is constant over time. Degradation **level** at time t , $\xi(t) = \beta_0 + \beta_1 t$, is linear in t . Examples include the amount of automobile tire tread wear, mechanical wear of a bearing, or a zero-order chemical reaction.

- **Concave degradation:** Degradation rate decreasing in time. Degradation level increasing at a decreasing rate. Examples include chemical processes with a limited amount of material to react (e.g., a first-order chemical reaction).
- **Convex degradation:** Degradation rate increasing in time. Degradation level increasing at an increasing rate. Examples include the Paris-law crack growth model.

Motivation for the Asymptotic Degradation Path Model Simple One-Step Chemical Reaction Leading to Failure

- $A_1(t)$ is the amount of harmful material at time t that is available for reaction to failure-causing A_2 .
- $A_2(t)$ is observable or proportional to an observable performance degradation $\mathcal{D}(t)$ at time t .
- Consider the chemical reaction:



- A soft failure occurs when $\mathcal{D}(t)$ exceeds the threshold \mathcal{D}_f
- The rate equations for this reaction are

$$\frac{dA_1}{dt} = -k_1 A_1 \quad \text{and} \quad \frac{dA_2}{dt} = k_1 A_1$$

where k_1 is the **reaction rate constant**.

Asymptotic Degradation Path Model

- The solution to the system of differential equations is:

$$\begin{aligned}A_1(t) &= A_1(0) \exp(-k_1 t) \\A_2(t) &= A_2(0) + A_1(0)[1 - \exp(-k_1 t)]\end{aligned}\tag{1}$$

where $A_1(0)$ and $A_2(0)$ are initial conditions.

- The asymptote for A_2 is

$$\mathcal{D}_\infty = \lim_{t \rightarrow \infty} A_2(t) = A_2(0) + A_1(0).$$

- The expression in (1) is the basis for the statistical model

$$Y = \xi(t) + \epsilon = \beta_0 + \beta_3[1 - \exp(-\beta_1 \tau)] + \epsilon$$

where $\tau = h_t(t)$ is (possibly) transformed time.

- Note that if $\mathcal{D}_f > \mathcal{D}_\infty$, there will never be a failure.
- A simple one-step diffusion process can be modeled in the same way.

Some Common Degradation Path Models

Model	$\xi(t)$	Description
1	$\beta_0 + \beta_1\tau$	\uparrow Linear
2	$\beta_0 - \beta_1\tau$	\downarrow Linear
3	$\beta_0 + \beta_3[1 - \exp(-\beta_1\tau)]$	\uparrow Asymptotic
4	$\beta_0 - \beta_3[1 - \exp(-\beta_1\tau)]$	\downarrow Asymptotic

Note that $\tau = h_t(t)$.

- Transformed time τ is a positive power transformation of t . Consequently, τ is a monotone increasing function of t .
- Note that $\beta_1 > 0$ and $\beta_3 > 0$ but β_0 is unrestricted in sign and may be constrained to be equal to 0 or some other value.
- Models 1 and 2 describe degradation that is **linear** in τ .
- Models 3 and 4 describe degradation that is **asymptotic** in τ .

Degradation Model Parameter Interpretation

- $\beta_0 = \xi(0)$ is the y intercept for all of the models.
- β_1 is the absolute value of the degradation rate (slope) for the linear models and the differential equation reaction rate constant for the asymptotic models.
- The asymptote of the **increasing** asymptotic degradation path Model 3 for large t is

$$\xi(\infty) = \lim_{t \rightarrow \infty} \xi(t) = \beta_0 + \beta_3.$$

- The asymptote of the **decreasing** asymptotic degradation path Model 4 for large t is

$$\xi(\infty) = \lim_{t \rightarrow \infty} \xi(t) = \beta_0 - \beta_3.$$

Some Common Degradation Path Regression Models

Model	$\xi(t, x, x_0)$	Description
5	$\beta_0 + \beta_1 \exp[-\beta_2(x - x_0)]\tau$	\uparrow Linear
6	$\beta_0 - \beta_1 \exp[-\beta_2(x - x_0)]\tau$	\downarrow Linear
7	$\beta_0 + \beta_3(1 - \exp\{-\beta_1 \exp[-\beta_2(x - x_0)]\tau\})$	\uparrow Asymptotic
8	$\beta_0 - \beta_3(1 - \exp\{-\beta_1 \exp[-\beta_2(x - x_0)]\tau\})$	\downarrow Asymptotic

Note that $\tau = h_t(t)$.

- Transformed time τ is a positive power transformation of t . Consequently, τ is a monotone increasing function of t .
- Models 5 and 6 describe **linear** degradation in τ .
- Models 7 and 8 describe **asymptotic** degradation in τ .
- The factor $AF = \exp[-\beta_2(x - x_0)]$ is a time-scaling acceleration factor (scaling transformed time τ) and $\beta_2 > 0$.
- If there are $p > 1$ explanatory variables, the factor $\exp[-\beta_2(x - x_0)]$ is replaced by

$$\exp[-\beta'_2(x - \bar{x})] = \exp\left[-\sum_{i=1}^p \beta_{2i}(x_i - x_{0,i})\right].$$

Degradation Regression Model

Parameter Interpretation

- $\beta_0 = \xi(0, x, x_0)$ is the y intercept for all of the models, is unrestricted in sign and may be constrained to be equal to 0 or some other value.
- $\beta_1 > 0$ is the absolute value of the degradation rate (slope) at x_0 for the linear models and the differential equation reaction rate constant at x_0 for the asymptotic models.
- **Note** that instead of x_0 , one can use any other value of x for this baseline value.
- For fixed x , the asymptote of the **increasing** asymptotic degradation path Model 7 for large t is

$$\xi(\infty, x, x_0) = \lim_{t \rightarrow \infty} \xi(t, x, x_0) = \beta_0 + \beta_3.$$

- For fixed x , the asymptote of the **decreasing** asymptotic degradation path Model 8 for large t is

$$\xi(\infty, x, x_0) = \lim_{t \rightarrow \infty} \xi(t, x, x_0) = \beta_0 - \beta_3.$$

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Segment 3

Destructive Degradation Background and an Example of Destructive Degradation Field Data Analysis

Destructive Degradation Data

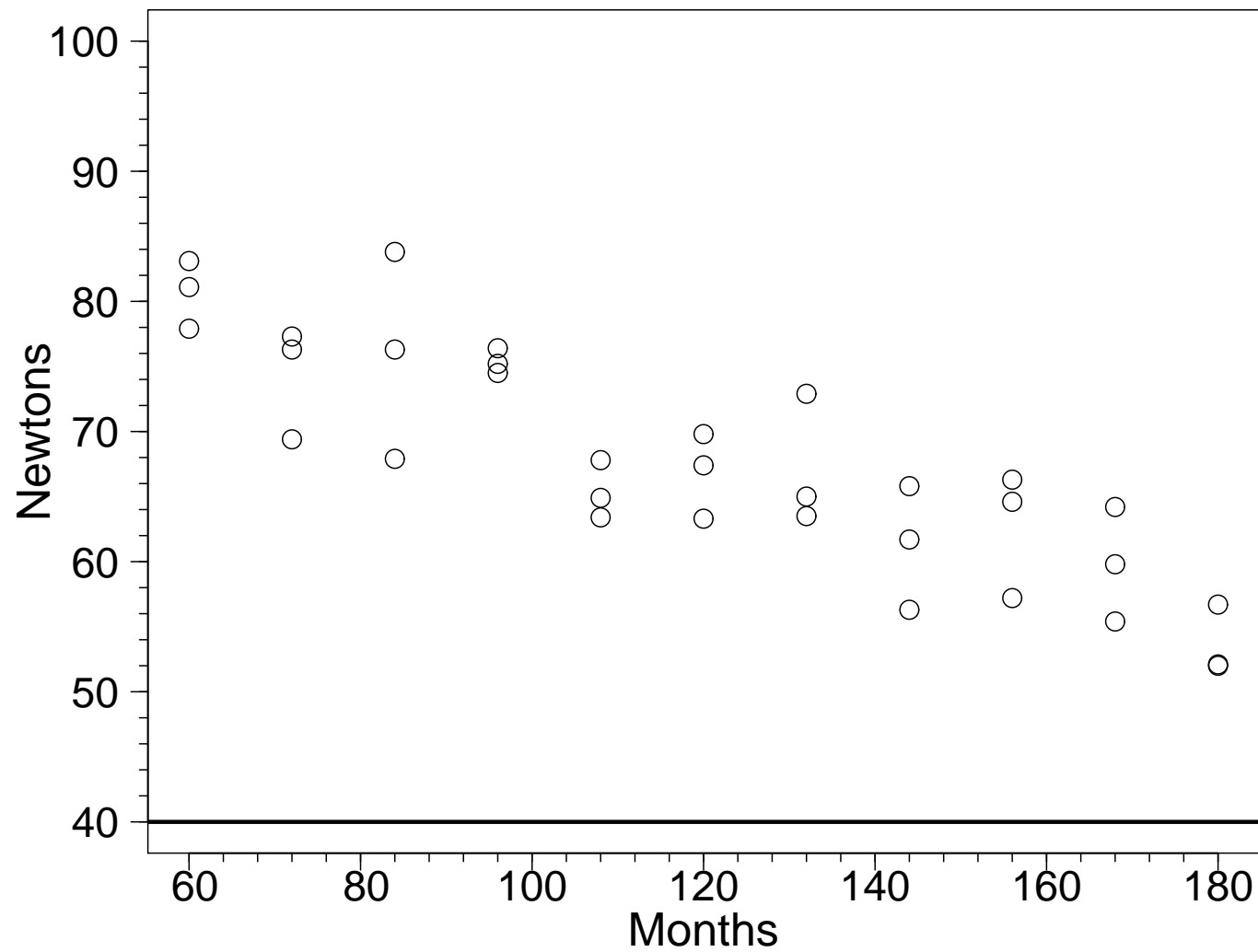
- Some degradation measurements are destructive.
- Examples include testing materials and components such as
 - ▶ Adhesive strength.
 - ▶ Dielectric strength of an insulating material.
 - ▶ Tensile strength of a polymer.
 - ▶ Strength of a seal.

Adhesive Bond A Strength Field Data

- An accelerated test estimated that the 0.01 quantile of the failure time distribution of **Adhesive Bond A** would be at least 20 years.
- Over the next 15 years, tens of thousands of the systems using Adhesive Bond A had been deployed in the field.
- There was concern that the large amount of extrapolation (in both the time and temperature dimension) might have provided overly optimistic lifetime estimates.
- Could the systems (originally designed for 15-year life) safely stay in service for 20 or 30 years?
- Three units were randomly selected from each of 11 age groups of the deployed systems having ages between 5 and 15 years, returned to the laboratory, and strengths of the 33 adhesive bonds were measured destructively.
- Want an estimate of the fraction failing (strength falling below 40 Newtons) after both 20 and 30 years.

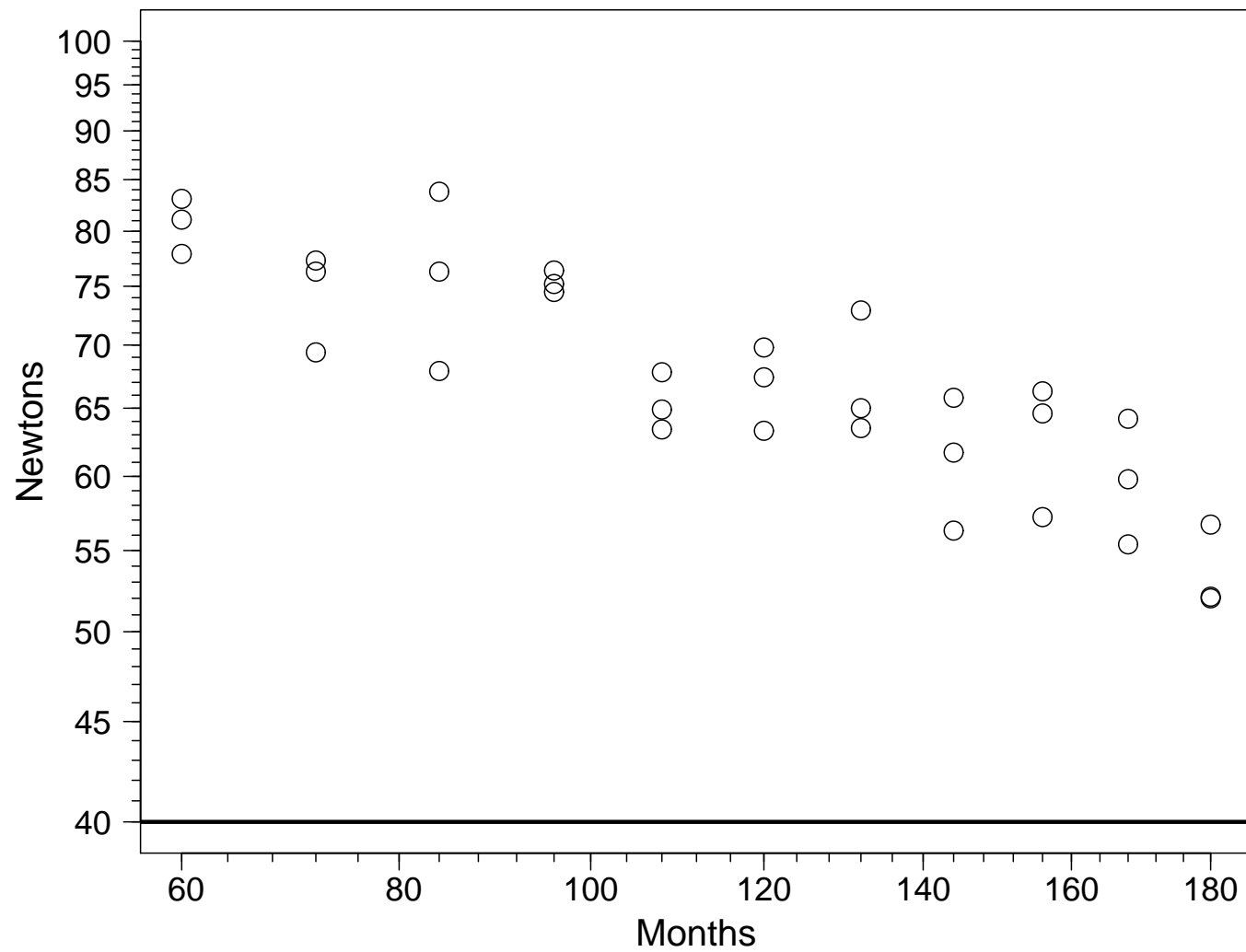
Adhesive Bond A Strength Field Data

Linear-Linear Axes



Adhesive Bond A Strength Field Data

Square Root–Log Axes



General Structure of Destructive Degradation Models

- Degradation model: $Y = \xi(t) + \epsilon$ where the path function $\xi(t)$ is monotone in t and ϵ has a location-scale distribution.
- Other forms could be used for $\xi(t)$.
- Time t can be viewed as a special kind of explanatory variable for Y .
- ϵ is an error term that describes unit-to-unit variability (and probably some measurement errors and model uncertainty that may not be independently estimable).
- The degradation distribution is:

$$G(y; t) = \Pr(Y \leq y) = \Phi \left[\frac{y - \xi(t)}{\sigma} \right].$$

For given value of t the p quantile of the distribution of Y is

$$y_p(t) = \xi(t) + \Phi^{-1}(p) \sigma.$$

Degradation Model

Likelihood with No Explanatory Variables

- For the data with exact observations and right-censored observations, the likelihood is

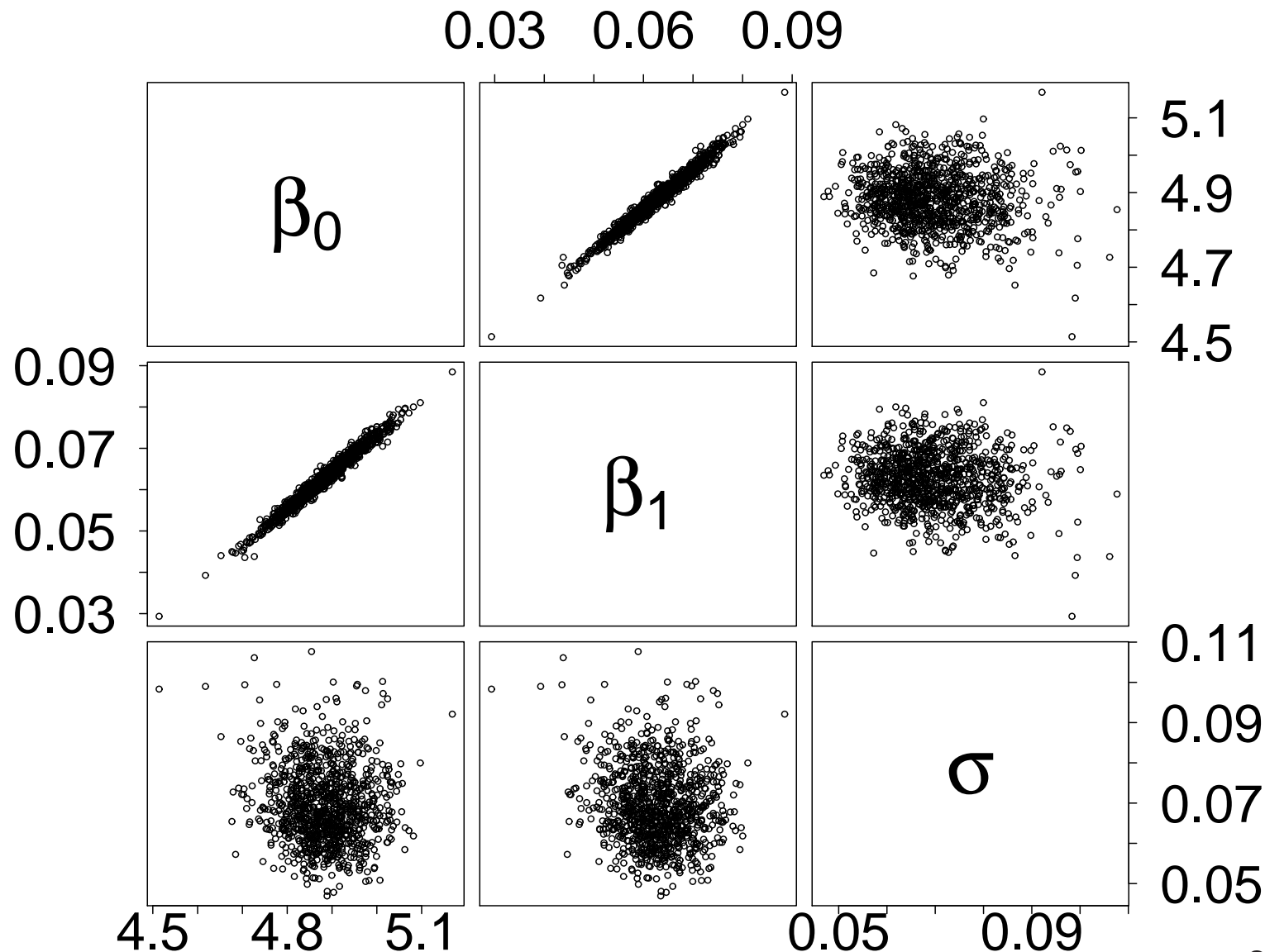
$$L(\boldsymbol{\theta}|\text{DATA}) = \prod_{i=1}^n \left[\frac{1}{\sigma} \phi\left(\frac{y_i - \xi(t_i)}{\sigma}\right) \right]^{\delta_i} \times \left[1 - \Phi\left(\frac{y_i - \xi(t_i)}{\sigma}\right) \right]^{1-\delta_i}.$$

- n is the number of observations.
- $\xi(t)$ is the chosen path model (say one of Models 1–4).
- The censoring indicator

$$\delta_i = \begin{cases} 1 & \text{if } y_i \text{ is an exact observation} \\ 0 & \text{if } y_i \text{ is a right-censored observation.} \end{cases}$$

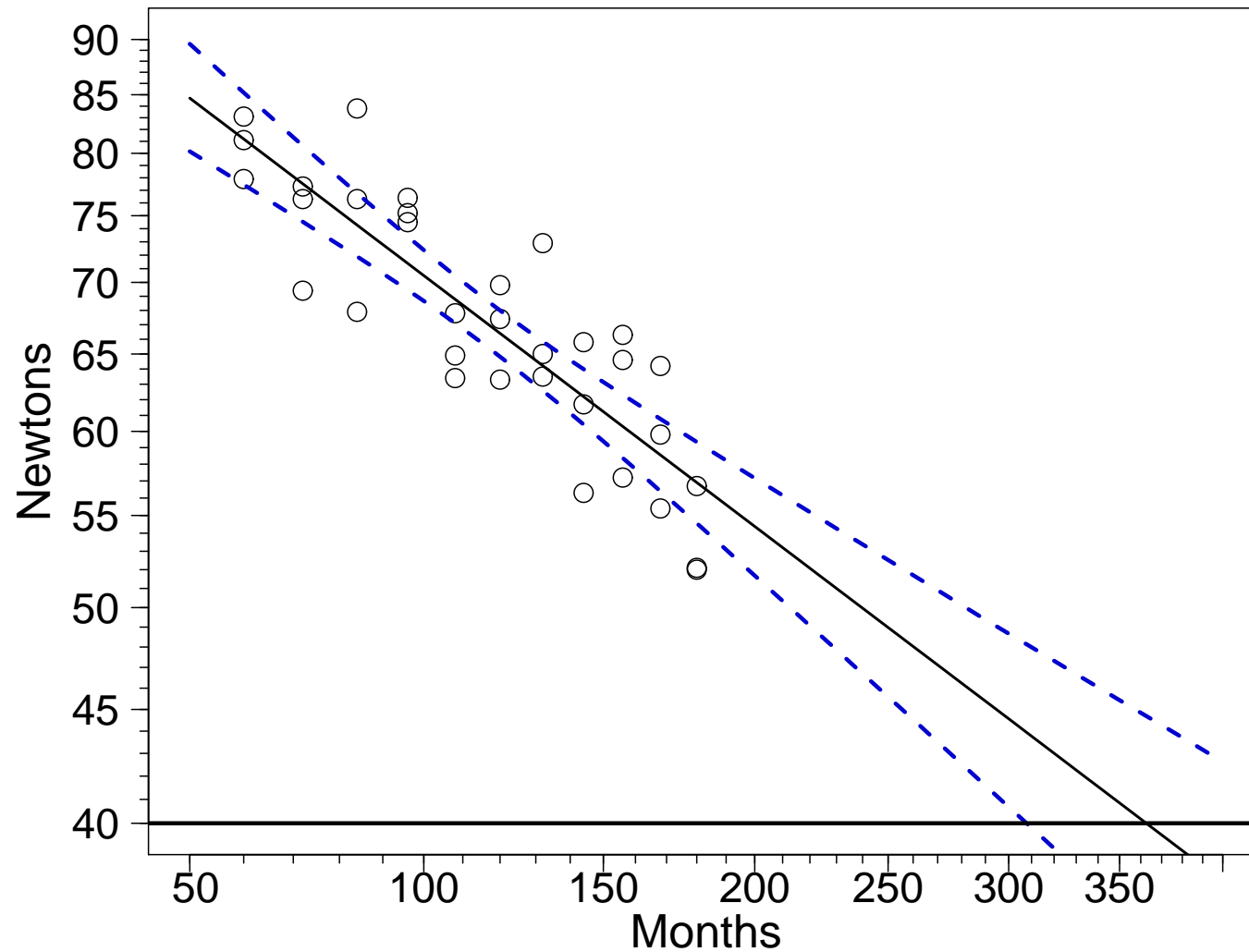
- $\boldsymbol{\theta} = (\beta_0, \beta_1, \sigma)$ for the linear models.
- $\boldsymbol{\theta} = (\beta_0, \beta_1, \beta_3, \sigma)$ for the asymptotic models.

Adhesive Bond A Strength Field Data
 Log/Square Root Transformation
 Weakly Informative Prior Distribution
 Posterior Pairs Plot $\hat{\xi}(t) = \hat{\beta}_0 - \hat{\beta}_1\tau$



**Adhesive Bond A Strength Field Data
and Fitted Model**

Normal Distribution Linear Path

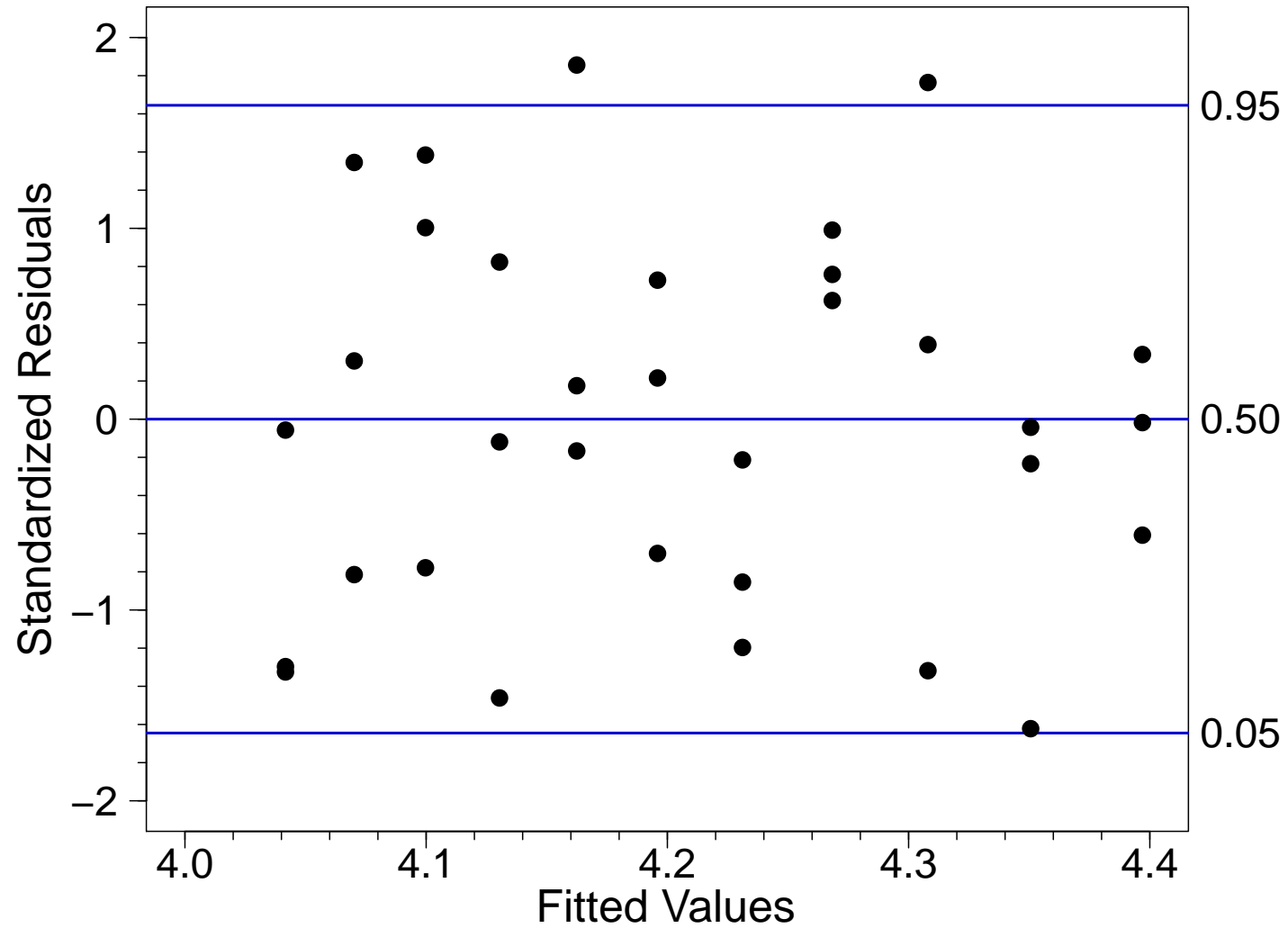
$$\hat{\xi}(t) = \hat{\beta}_0 - \hat{\beta}_1 \tau$$


Adhesive Bond A Strength Field Data
Bayesian Parameter Estimates
Normal Distribution Linear Path Model

Parameter	Estimate	Standard Error	95% Credible Interval	
			Lower	Upper
β_0	4.49	0.01	4.46	4.51
β_1	0.37	0.02	0.33	0.40
σ	0.05	0.005	0.04	0.06

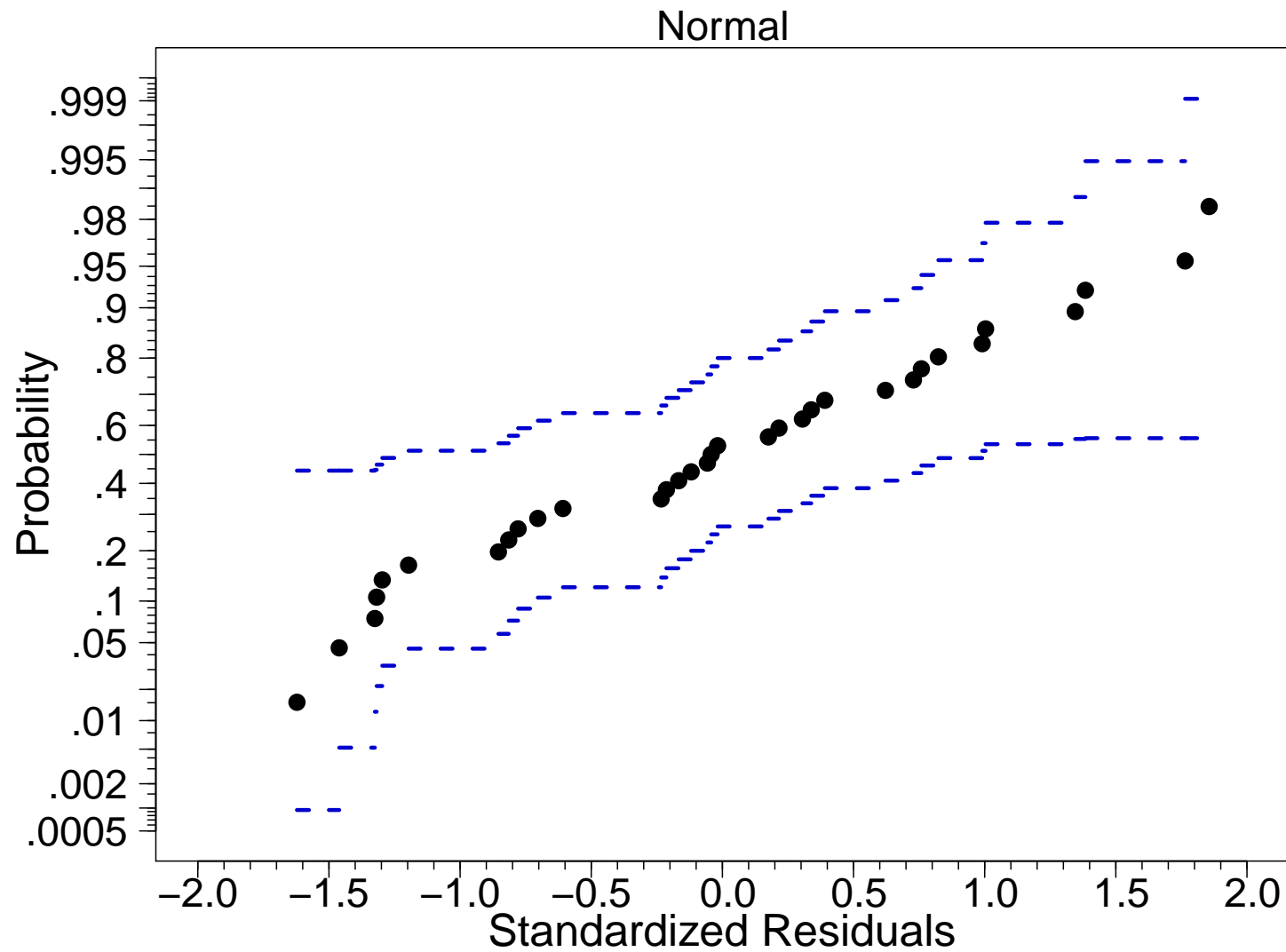
Adhesive Bond A Strength Field Data

Residuals Versus Fitted Values



Adhesive Bond A Strength Field Data

Normal Distribution Residual Probability Plot



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Degradation Modeling and Destructive Degradation Data Analysis

Segment 4

Failure-Time Distributions Induced from Destructive Degradation Models and Failure-Time Inferences

A General Approach to Obtaining the Failure Time Distribution for Increasing Destructive Degradation Models

For increasing degradation, the failure time T of a unit is defined to be the time that its observed degradation exceeds a critical value \mathcal{D}_f . The event $T \leq t$ is equivalent to observed degradation being greater than or equal to \mathcal{D}_f [i.e., $Y \geq h_d(\mathcal{D}_f)$]. Then,

$$F(t, x) = \Pr(T \leq t) = 1 - \Phi \left[\frac{h_d(\mathcal{D}_f) - \xi(t, x)}{\sigma} \right], \text{ for } t \geq 0.$$

$$t_p = \begin{cases} 0 & \text{if } p \leq F(0, x) \\ \xi^{-1} [h_d(\mathcal{D}_f) - \sigma \Phi^{-1}(1 - p)] & \text{if } F(0, x) < p < F(\infty, x) \\ \infty & \text{if } F(\infty, x) < p, \end{cases}$$

where for given x , $\xi^{-1}(w)$ is the unique solution for t in the equation $\xi(t, x) = w$. That is, $\xi[\xi^{-1}(w), x] = w$.

A General Approach to Obtaining the Failure Time Distribution for Decreasing Destructive Degradation Models

For decreasing degradation, $T \leq t$ is equivalent to observed degradation being less than or equal to \mathcal{D}_f [i.e., $Y \leq h_d(\mathcal{D}_f)$]. Then,

$$F(t, x) = \Pr(T \leq t) = \Phi \left[\frac{h_d(\mathcal{D}_f) - \xi(t, x)}{\sigma} \right], \text{ for } t \geq 0.$$

$$t_p = \begin{cases} 0 & \text{if } p \leq F(0, x) \\ \xi^{-1} \left[h_d(\mathcal{D}_f) - \sigma \Phi^{-1}(p) \right] & \text{if } F(0, x) < p < F(\infty, x) \\ \infty & \text{if } F(\infty, x) < p. \end{cases}$$

Induced Failure Time Distribution for the Linear Degradation Model 2 (Decreasing Degradation)

- For Model 2 $T \leq t$ is equivalent to observed degradation being less than or equal to \mathcal{D}_f [i.e., $Y \leq h_d(\mathcal{D}_f)$]. Then

$$F(t) = \Pr[Y \leq h_d(\mathcal{D}_f)] = \Phi \left[\frac{h_d(\mathcal{D}_f) - \xi(t)}{\sigma} \right], \text{ for } t \geq 0.$$

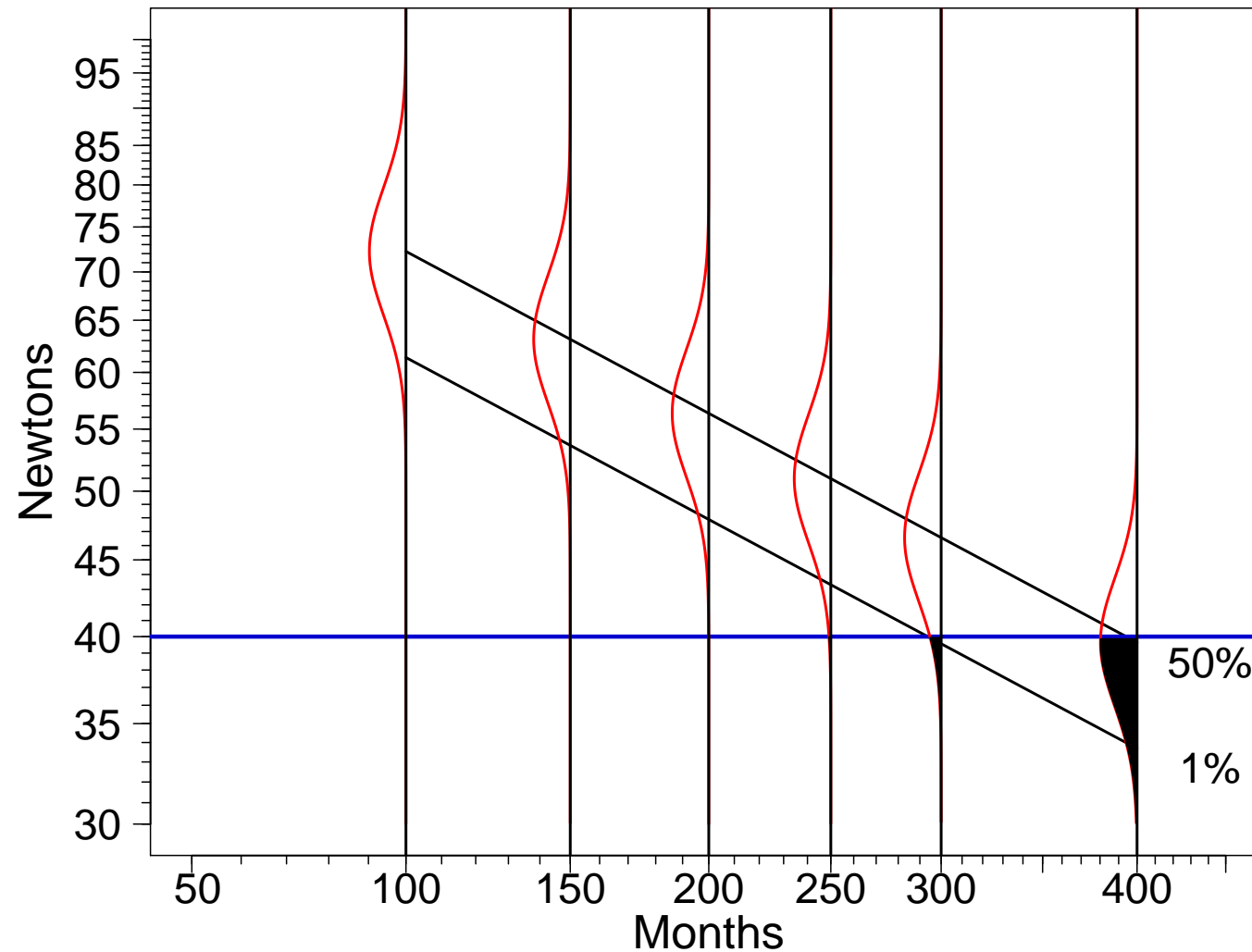
- This failure time distribution is a mixed distribution with a probability **atom** at $t = 0$ and probability

$$\Pr(T = 0) = F(0) = \Phi \left[\frac{h_d(\mathcal{D}_f) - \beta_0}{\sigma} \right].$$

Adhesive Bond A

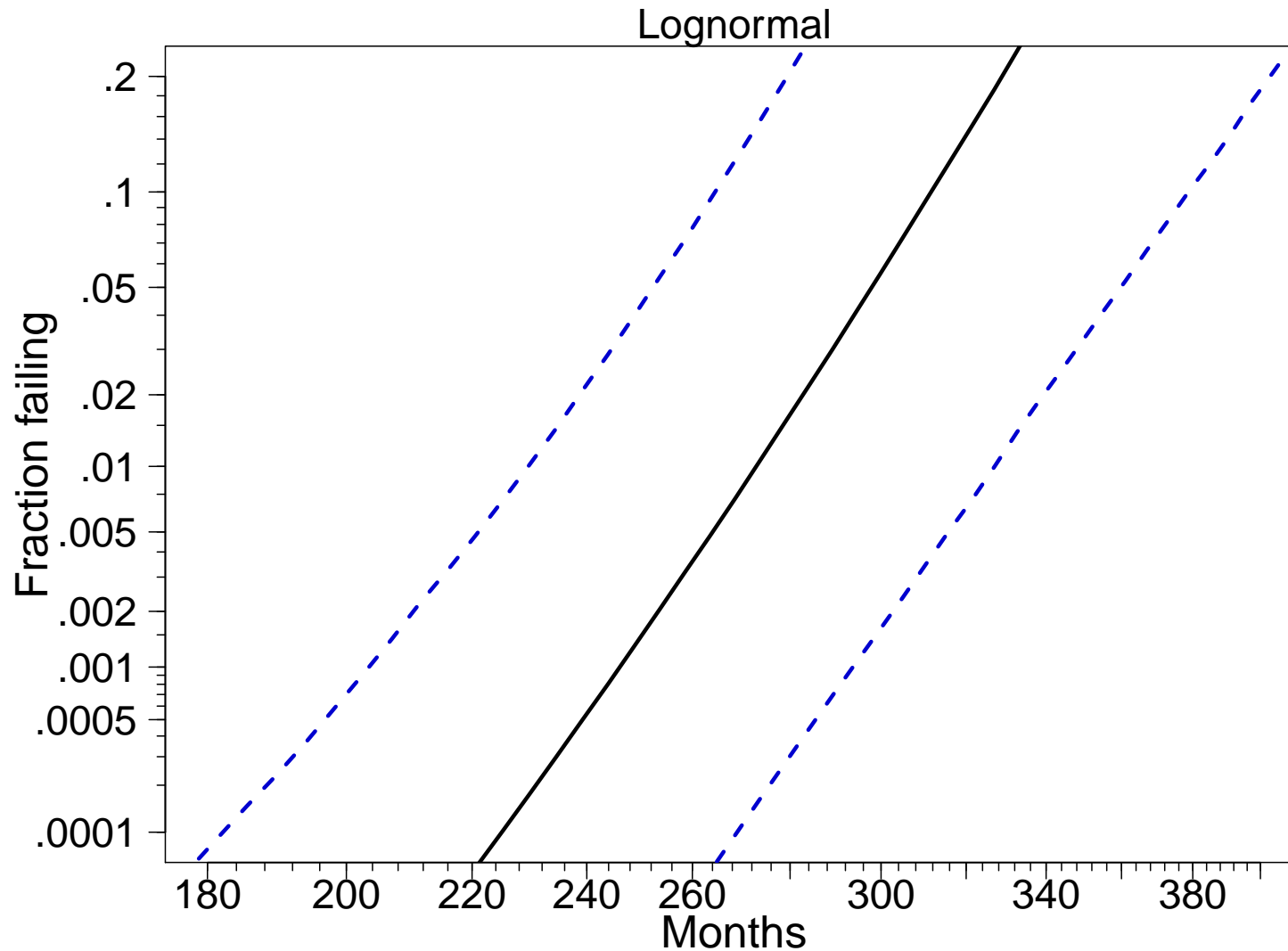
Estimate of Fraction Failing as a Function of Time

$$\hat{y}_p = \hat{\beta}_0 - \hat{\beta}_1 \tau + \hat{\sigma} \Phi_{\text{norm}}^{-1}(p)$$



Adhesive Bond A

Lognormal Probability Plot of the Failure-Time cdf Estimate and 95% Credible Intervals



Quantiles for the Failure Time Distribution at Fixed Values of \mathcal{D}_f for Model 2

For Model 2, the p quantile is $t_p = h_t^{-1}(\tau_p)$, where

$$\tau_p = \begin{cases} 0 & \text{if } p \leq F(0) \\ \frac{1}{\beta_1} [\beta_0 - h_d(\mathcal{D}_f) + \Phi^{-1}(p)\sigma] & \text{if } p > F(0), \end{cases}$$

where $F(0) = \Phi \left[\frac{h_d(\mathcal{D}_f) - \beta_0}{\sigma} \right]$.

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Degradation Modeling and Destructive Degradation Data Analysis

Segment 5

Background and an Example of Accelerated Destructive Degradation Testing (ADDT) and Model Building.

Accelerated Destructive Degradation Test of Adhesive Bond B

- **Objective:** Assess the strength of an **adhesive bond** as a function of time. Estimate the fraction of devices with a strength below 40 Newtons after 5 years of operation (approximately 260 weeks) at 25°C.
- The test is destructive; each unit can be measured only once.
- There were 6 right-censored observations.
- 8 units with no aging were measured at the start of the experiment.
- A total of 80 additional units were aged and measured according to a temperatures and time schedule.

Adhesive Bond B ADDT Test Plan

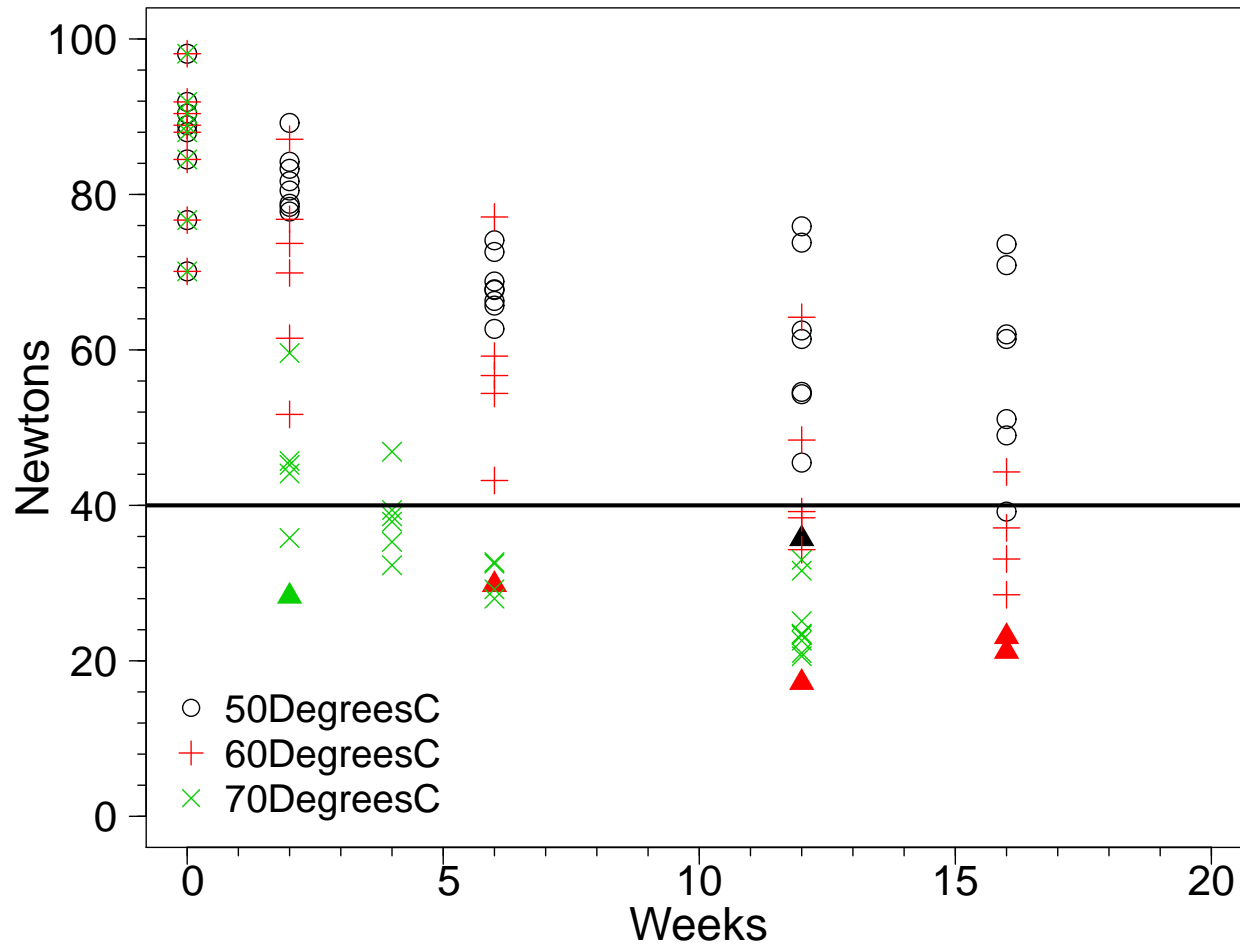
Number of Specimens Tested

Temp °C	Weeks Aged						Totals
	0	2	4	6	12	16	
—	8						8
50		8	0	8	8	7	31
60		6	0	6	6	6	24
70		6	6	4	9	0	25
Totals	8	20	6	18	23	13	88

Adhesive Bond B ADDT Data

Scatter Plot

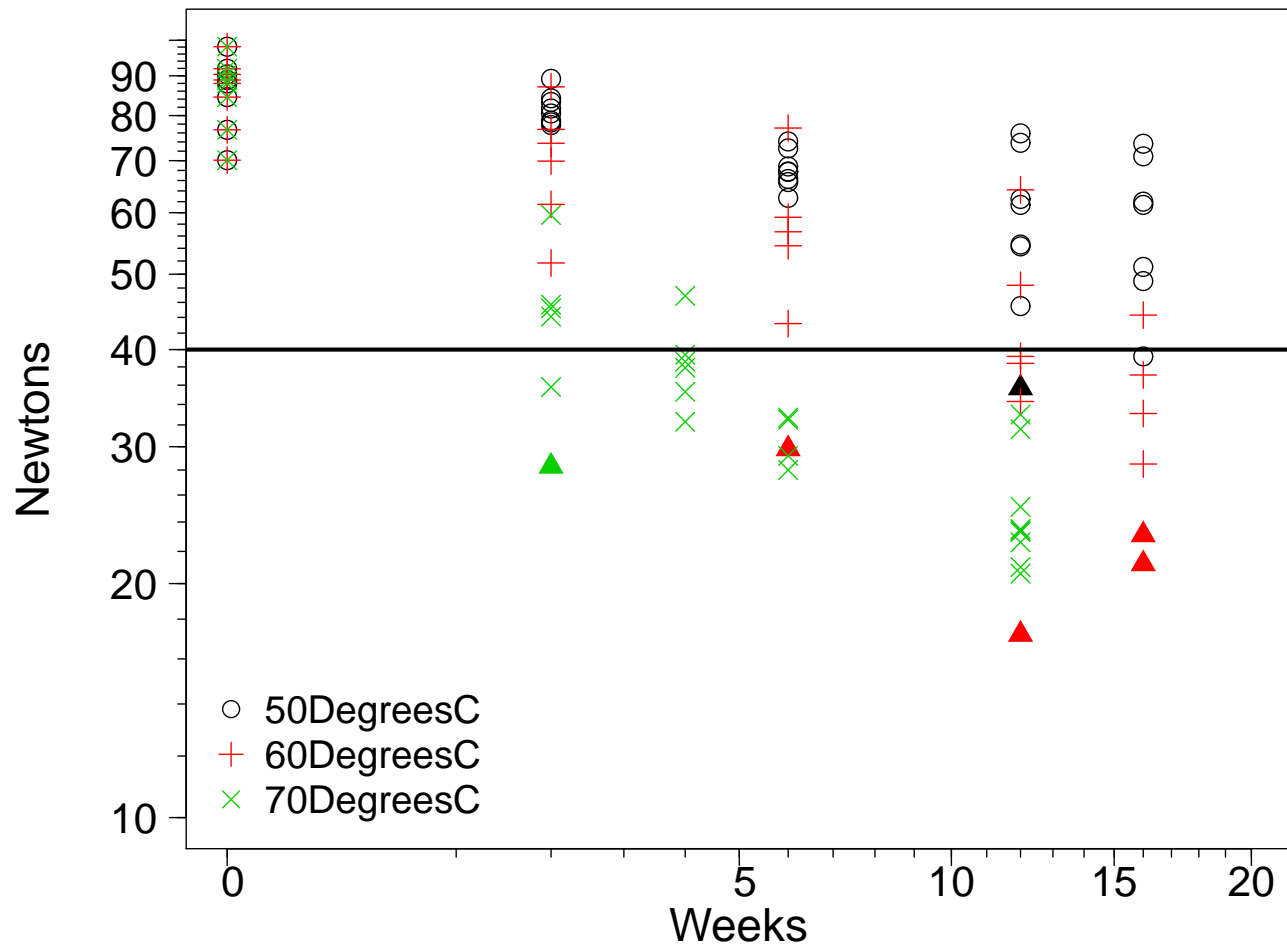
Linear-Linear Axes



Adhesive Bond B ADDT Data

Scatter Plot

Square Root–Log Axes

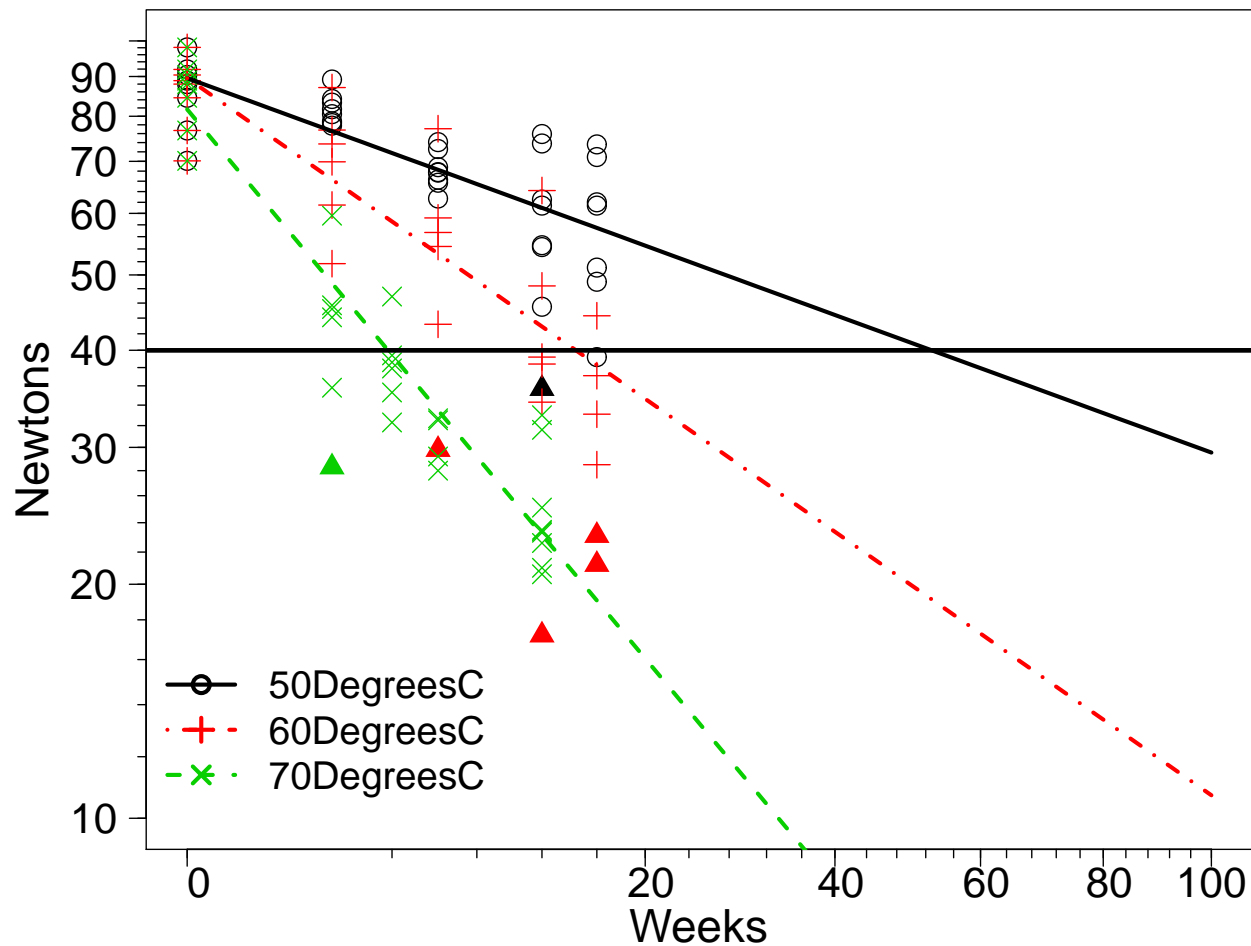


Adhesive Bond B ADDT Data

Overlay of Individual Normal Distribution Fits

Square Root–Log Axes

$$\hat{\xi}^{[j]}(t) = \hat{\beta}_0^{[j]} + \hat{\beta}_1^{[j]} \tau, \quad j = 50, 60, 70$$



General Structure of Destructive Degradation Regression Models

- Degradation model: $Y = \xi(t, x) + \epsilon$, where for fixed x , path $\xi(t, x)$ is monotone in t and ϵ has location-scale distribution with parameters $\mu = 0$ and σ .
- Other forms could be used for $\xi(t, x)$.
- Time t can be viewed as a special kind of explanatory variable for Y .
- ϵ is an error term that describes unit-to-unit variability (and probably some measurement errors and model uncertainty that may not be independently estimable).
- The degradation distribution and its quantile:

$$G(y; t, x) = \Pr(Y \leq y) = \Phi \left[\frac{y - \xi(t, x)}{\sigma} \right].$$

For given (t, x) , the p quantile for the cdf $G(y; t, x)$ is

$$y_p(t, x) = \xi(t, x) + \Phi^{-1}(p) \sigma.$$

Adhesive Bond B ADDT Data

Bayesian Estimates

Linear Path Normal Distribution Individual Line Fits

- For each temperature level j three individual estimates are obtained: $\hat{\beta}_0^{[j]}$, $\hat{\beta}_1^{[j]}$, and $\hat{\sigma}^{[j]}$.
- A summary of the linear path normal distribution estimates for individual temperatures for the Adhesive Bond B data is

Temperature	Estimates			95% Credible Interval for $\hat{\beta}_1^{[j]}$	
	$\hat{\beta}_0^{[j]}$	$\hat{\beta}_1^{[j]}$	$\hat{\sigma}^{[j]}$	$\tilde{\beta}_1^{[j]}$	$\tilde{\beta}_1^{[j]}$
50°C	4.50	0.11	0.14	0.08	0.14
60°C	4.50	0.21	0.17	0.17	0.26
70°C	4.40	0.36	0.15	0.32	0.40

Individual Degradation Rate Estimates

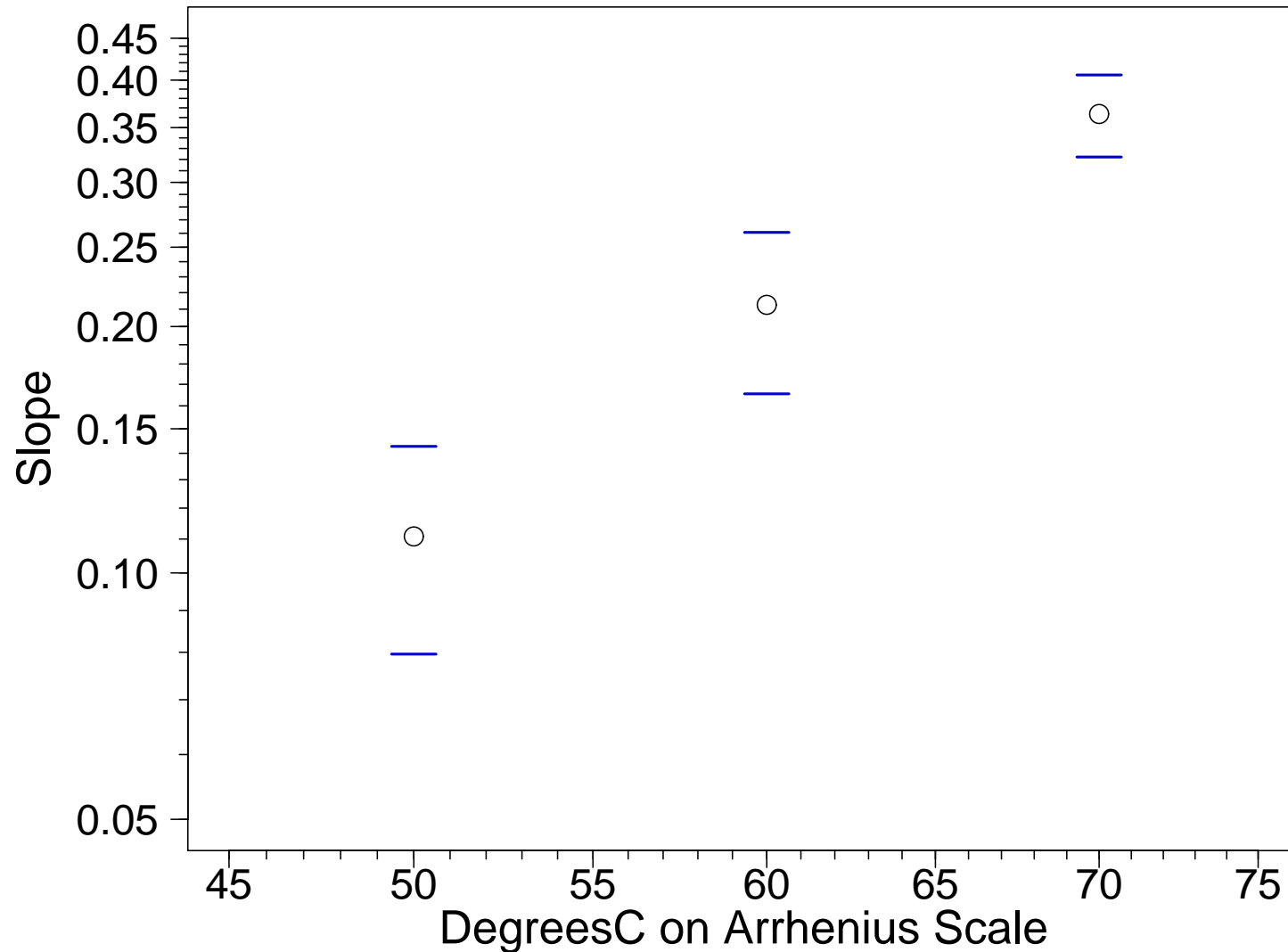
- The estimates $\hat{\beta}_1^{[j]}$ (slopes of the individual lines at test condition j) can be used to identify the relationship between the degradation rate and the accelerating variables.
- Taking the log of the slope in Model 6 gives

$$\log(\beta_1^{[j]}) = \log(\beta_1) - \beta'_2(x_j - \bar{x}_j)$$

the surface $\log(\hat{\beta}_1^{[j]})$ versus x_j should be approximately linear in the x_j if the model relating degradation rate and the accelerating variables is adequate. Then

- ▶ For a single accelerating variable x , the plot of $\log(\hat{\beta}_1^{[j]})$ versus x_j , for all values of j should be approximately linear.
- ▶ For a vector \mathbf{x} the plot of $\log(\hat{\beta}_1^{[j]})$ versus any of the accelerating variables, conditional on fixed values of the remaining accelerating variables, should be approximately linear.

Adhesive Bond B ADDT Data Arrhenius Plot of Individual Degradation Rate Estimates $\hat{\beta}_1^{[j]}$ versus °C Normal Distribution Estimates



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Degradation Modeling and Destructive Degradation Data Analysis

Segment 6

Fitting an Acceleration Model to ADDT Data

Linear-Path Acceleration Model for the Adhesive Bond B Data

For the Adhesive Bond B data, the strength of the adhesive as a function of time and temperature is modeled by

$$\begin{aligned} Y_i &= \xi(t_i, x_i) + \epsilon_i \\ &= \beta_0 - \beta_1 \exp[-\beta_2(x_i - x_0)]\tau_i + \epsilon_i \end{aligned}$$

where

$$Y_i = \log(\text{Newtons}_i)$$

$$\tau_i = \sqrt{t_i} = \sqrt{\text{Weeks}_i}$$

$$x_i = 11604.52/({}^\circ\text{C}_i + 273.15)$$

$$x_0 = 50^\circ\text{C}$$

$$\epsilon_i \sim \text{NORM}(0, \sigma), \quad i = 1, \dots, n.$$

Likelihood for the ADDT Model with Right Censored Data

- For a sample of n units consisting of exact failure times and right-censored observations, the likelihood can be expressed as

$$L(\boldsymbol{\theta}|\text{DATA}) = \prod_{i=1}^n \left[\frac{1}{\sigma} \phi\left(\frac{y_i - \xi(t_i, x_i)}{\sigma}\right) \right]^{\delta_i} \times \left[1 - \Phi\left(\frac{y_i - \xi(t_i, x_i)}{\sigma}\right) \right]^{1-\delta_i}.$$

- n is the number of observations.
- $\xi(t, x_i)$ is the chosen path model (say one of Models 5–8).
- The censoring indicator

$$\delta_i = \begin{cases} 1 & \text{if } y_i \text{ is an exact observation} \\ 0 & \text{if } y_i \text{ is a right-censored observation.} \end{cases}$$

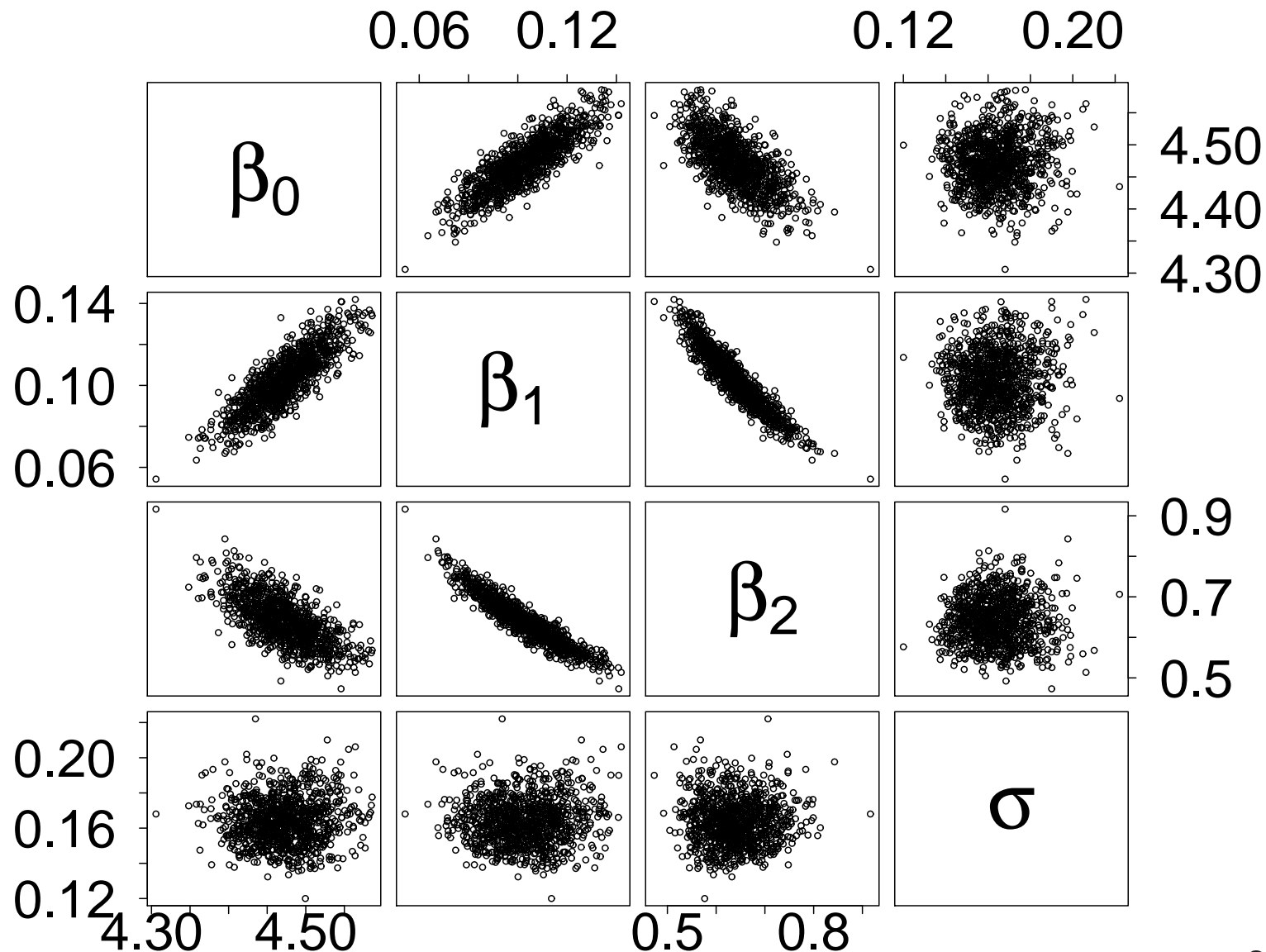
- $\boldsymbol{\theta} = (\beta_0, \beta_1, \beta_2, \sigma)$ for the linear models.
- $\boldsymbol{\theta} = (\beta_0, \beta_1, \beta_2, \beta_3, \sigma)$ for the asymptotic models.

Adhesive Bond B Strength Data

Log/Square Root Transformation

Weakly Informative Prior Distribution

Posterior Pairs Plot



Adhesive Bond B ADDT Data

Bayesian Parameter Estimates

Normal Distribution Linear Path Arrhenius Model

Parameter	Estimate	Standard Error	95% Credible Interval	
			Lower	Upper
β_0	4.47	0.04	4.39	4.55
β_1	0.10	0.01	0.08	0.13
β_2	0.64	0.06	0.54	0.77
σ	0.16	0.01	0.14	0.19

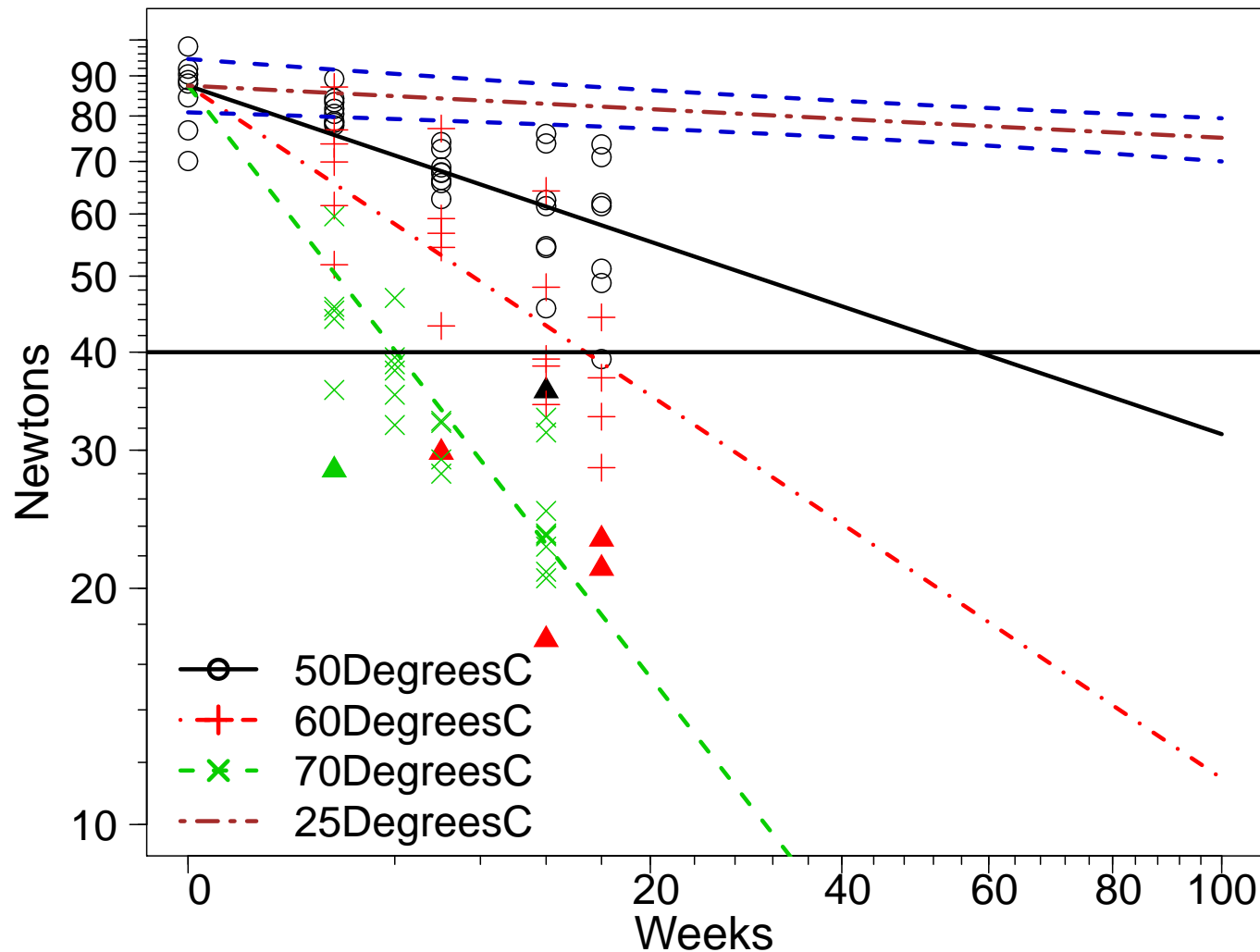
Estimates for the slopes (degradation rates) at each temperature are obtained from $\hat{\beta}_1^{[j]} = \hat{\beta}_1 \exp[-\hat{\beta}_2(x - x_0)]$ where $x = 11604.52/(\text{°C} + 273.15)$ and $x_0 = 50\text{°C}$. In this case for the four temperatures of interest, the estimates are

$$\begin{aligned} \hat{\beta}_1^{[25]} &= 0.015, & \hat{\beta}_1^{[50]} &= 0.101 \\ \hat{\beta}_1^{[60]} &= 0.202, & \hat{\beta}_1^{[70]} &= 0.388 \end{aligned}$$

Adhesive Bond B ADDT Data and Fitted Model

Normal Distribution Linear Path Arrhenius Model

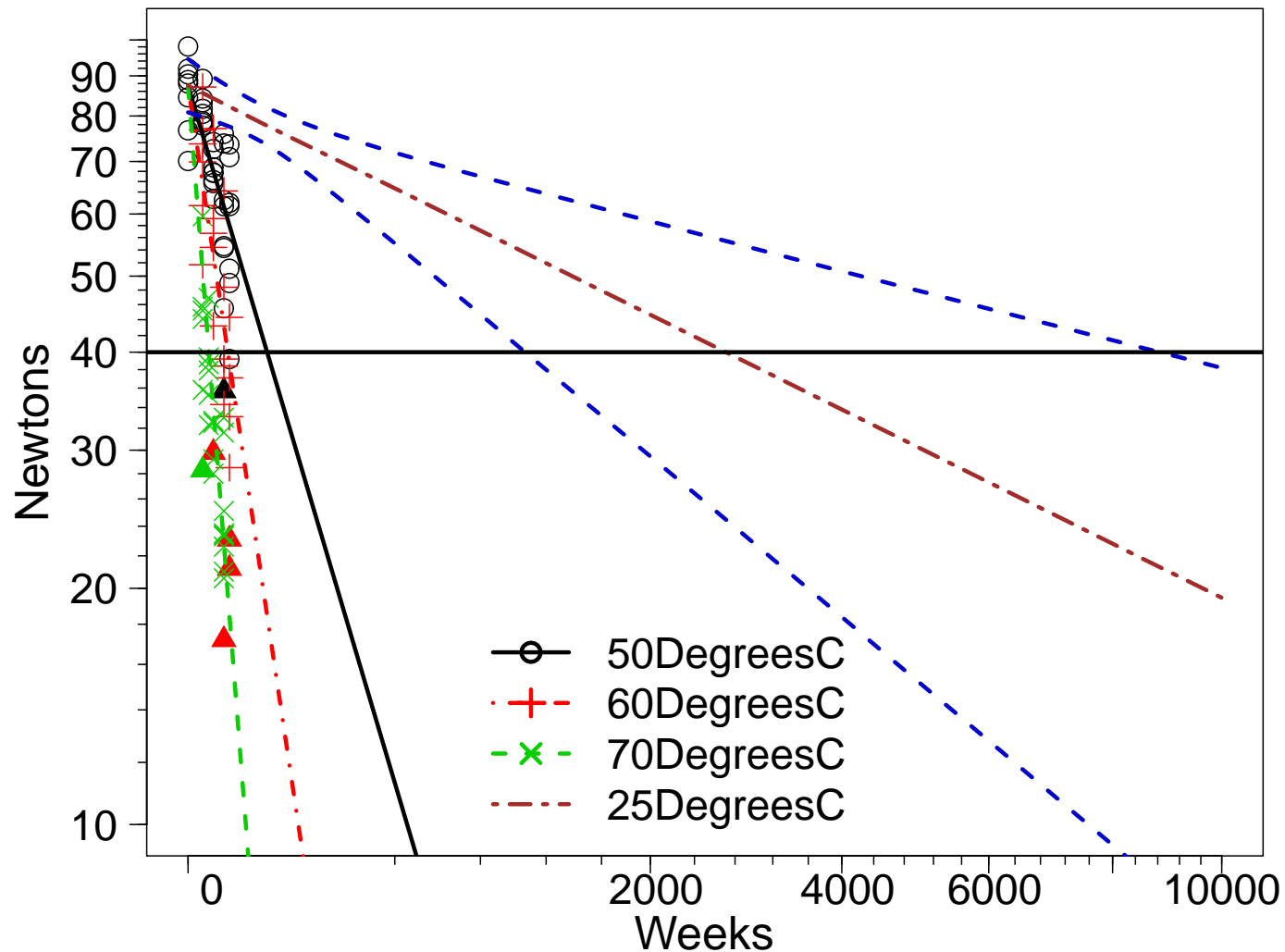
$$\hat{\xi}(t, x) = \hat{\beta}_0 - \hat{\beta}_1 \exp[-\hat{\beta}_2(x - x_0)]\tau$$



Adhesive Bond B ADDT Data and Fitted Model

Normal Distribution Linear Path Arrhenius Model

$$\hat{\xi}(t, x) = \hat{\beta}_0 - \hat{\beta}_1 \exp[-\hat{\beta}_2(x - x_0)]\tau$$



Chapter 20

**Degradation Modeling
and Destructive Degradation Data Analysis**

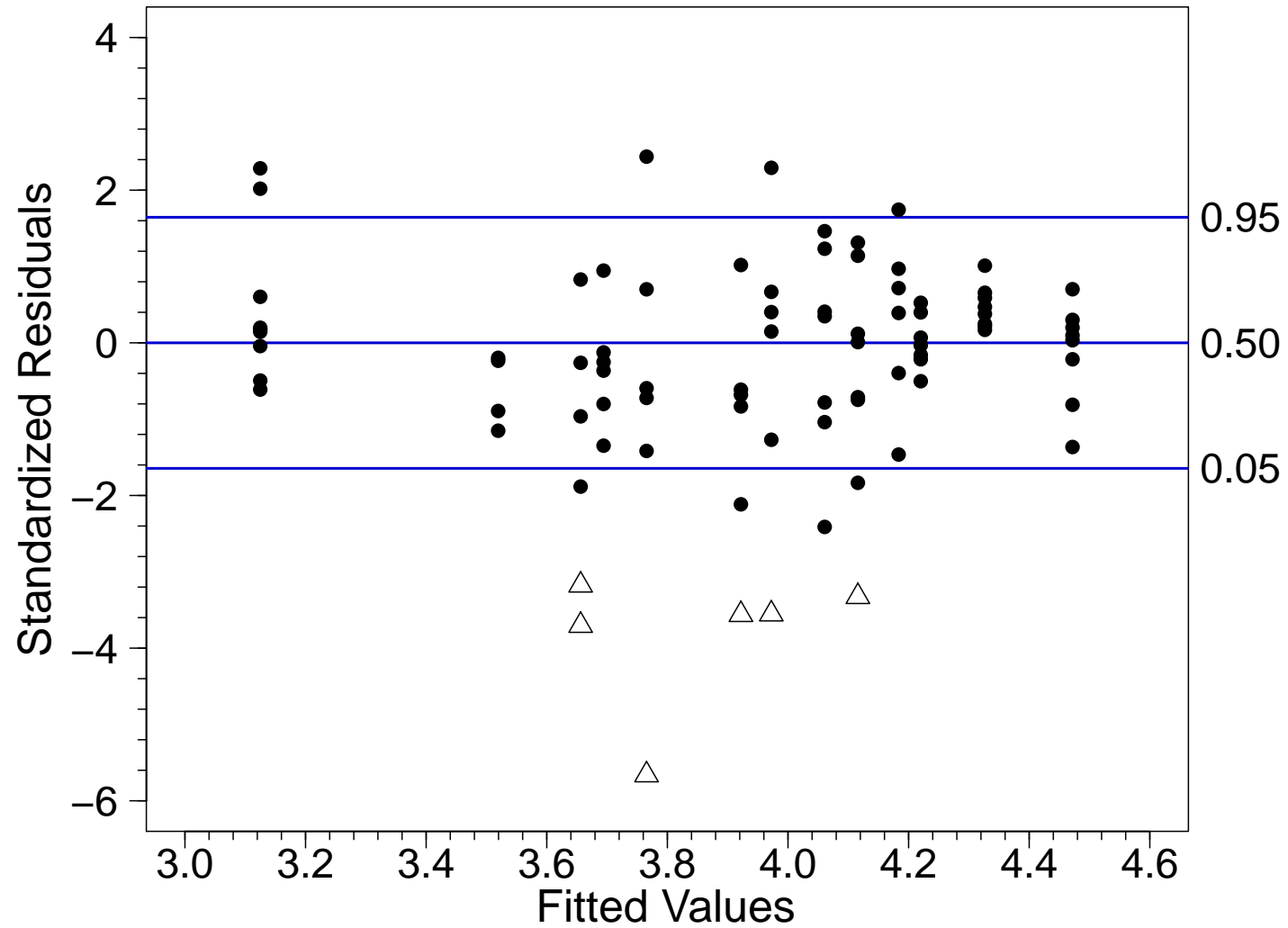
Segment 7

ADDT Model Checking

ADDT Model Checking Residual Plots

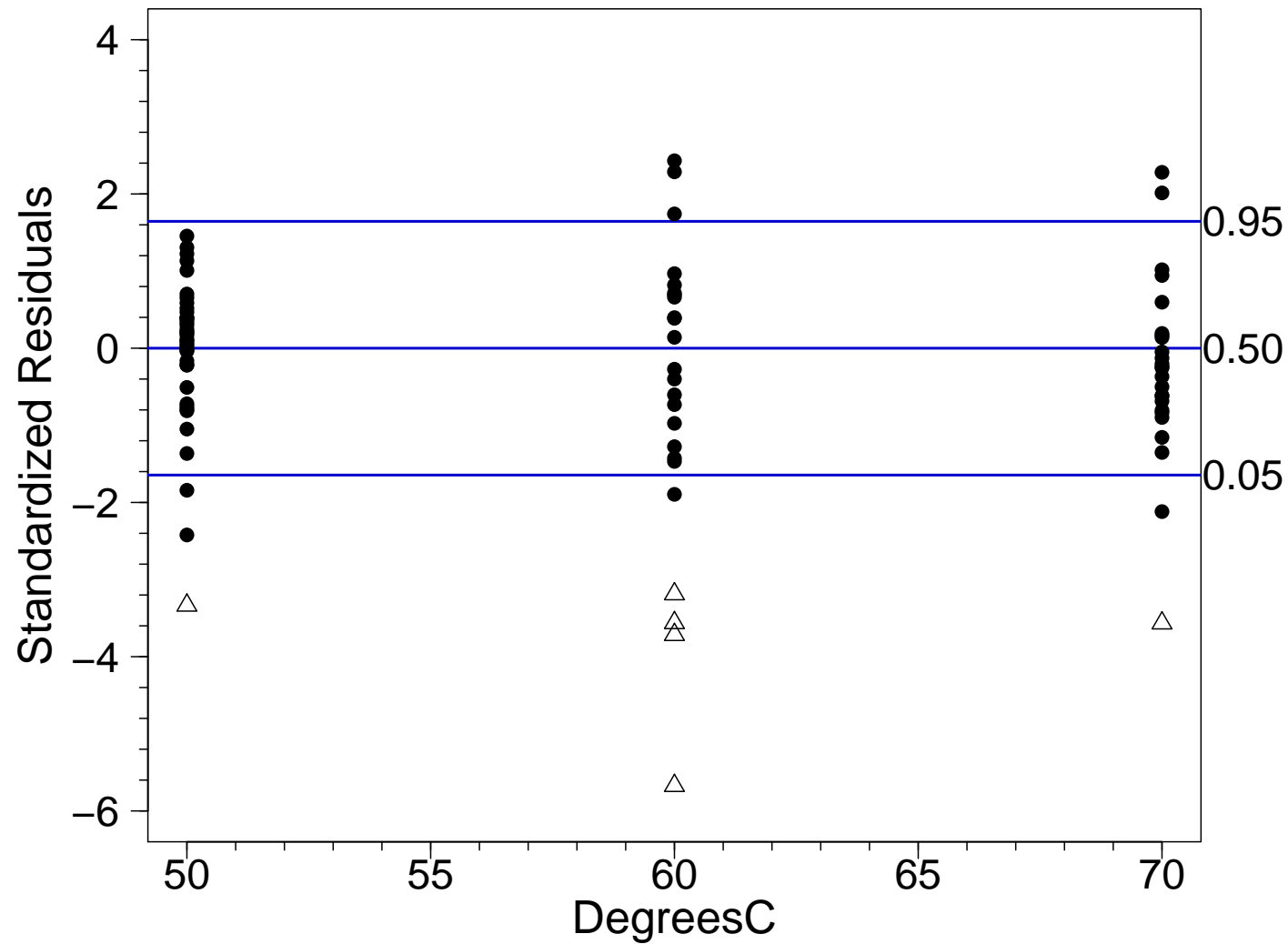
- Residuals versus fitted values.
- Residuals versus accelerating variables.
- Residuals versus time of exposure.
- Residuals versus observation order is useful when observations are taken sequentially in time.
- Residual probability plot.

Adhesive Bond B ADDT Data Residuals Versus Fitted Values



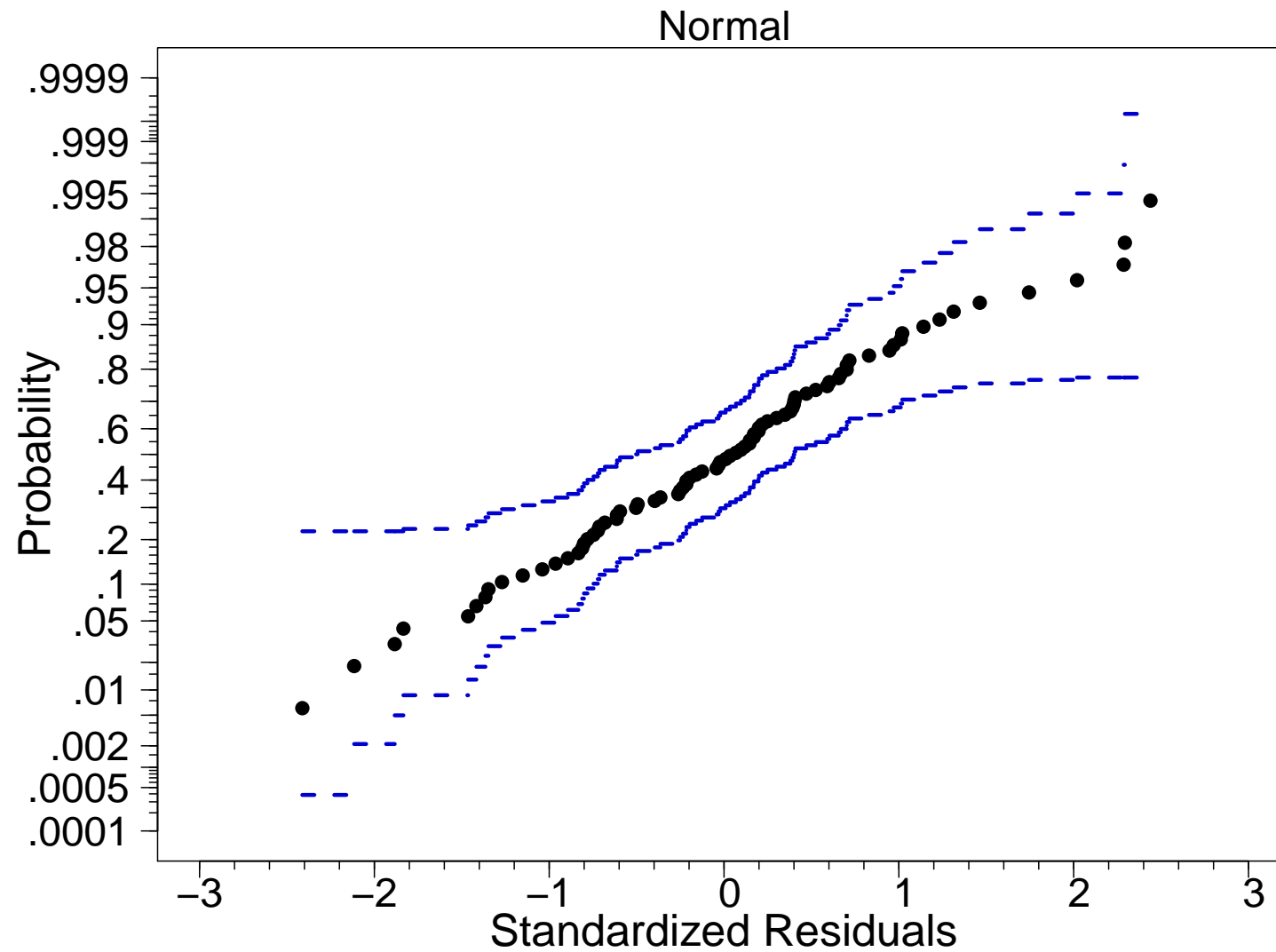
Adhesive Bond B ADDT Data

Residuals Versus Temperature Conditions



Adhesive Bond B ADDT Data

Residual Normal Distribution Probability Plot



Some Comments on the Adhesive Bond B Residuals

- The standardized residuals look approximately like a random sample from a $NORM(0, 1)$ distribution.
- The horizontal line at 0 in the plot versus fitted values and versus temperature indicate the median of the standardized distribution under the fitted model. Then approximately 50% of the residuals should be above that line.
- There appears to be some evidence of nonconstant variance, but it is not systematic with temperature or times.

Chapter 20

Degradation Modeling and Destructive Degradation Data Analysis

Segment 8

ADDT Failure-Time Distribution Inferences

Induced Failure Time Distribution for the Linear Degradation Model 6 (Decreasing Degradation)

- For Model 6, $T \leq t$ is equivalent to degradation being less than or equal to \mathcal{D}_f [i.e., $Y \leq h_d(\mathcal{D}_f)$]. Then

$$\begin{aligned} F(t, x) &= \Pr(T \leq t) = \Pr[Y \leq h_d(\mathcal{D}_f)] \\ &= \Phi \left[\frac{h_d(\mathcal{D}_f) - \xi(t, x)}{\sigma} \right], \text{ for } t \geq 0. \end{aligned}$$

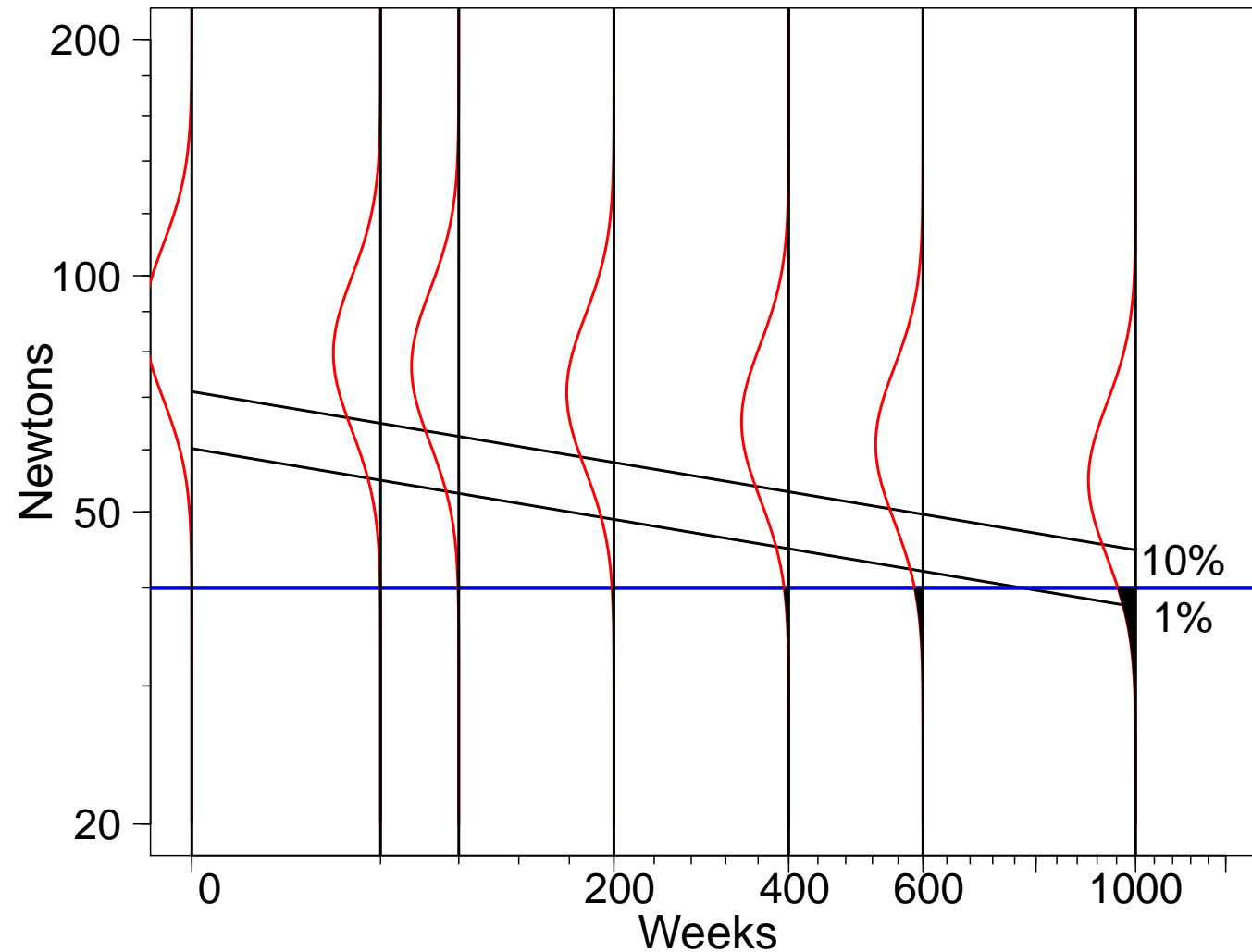
- This failure time distribution is a mixed distribution with a probability **atom** at $t = 0$ so

$$\begin{aligned} \Pr(T = 0, x) &= F(0, x) = \Pr(Y \leq h_d(\mathcal{D}_f)) \\ &= \Phi \left[\frac{h_d(\mathcal{D}_f) - \beta_0}{\sigma} \right]. \end{aligned}$$

Adhesive Bond B

Estimates of Fraction Failing as a Function of Time at 25°C

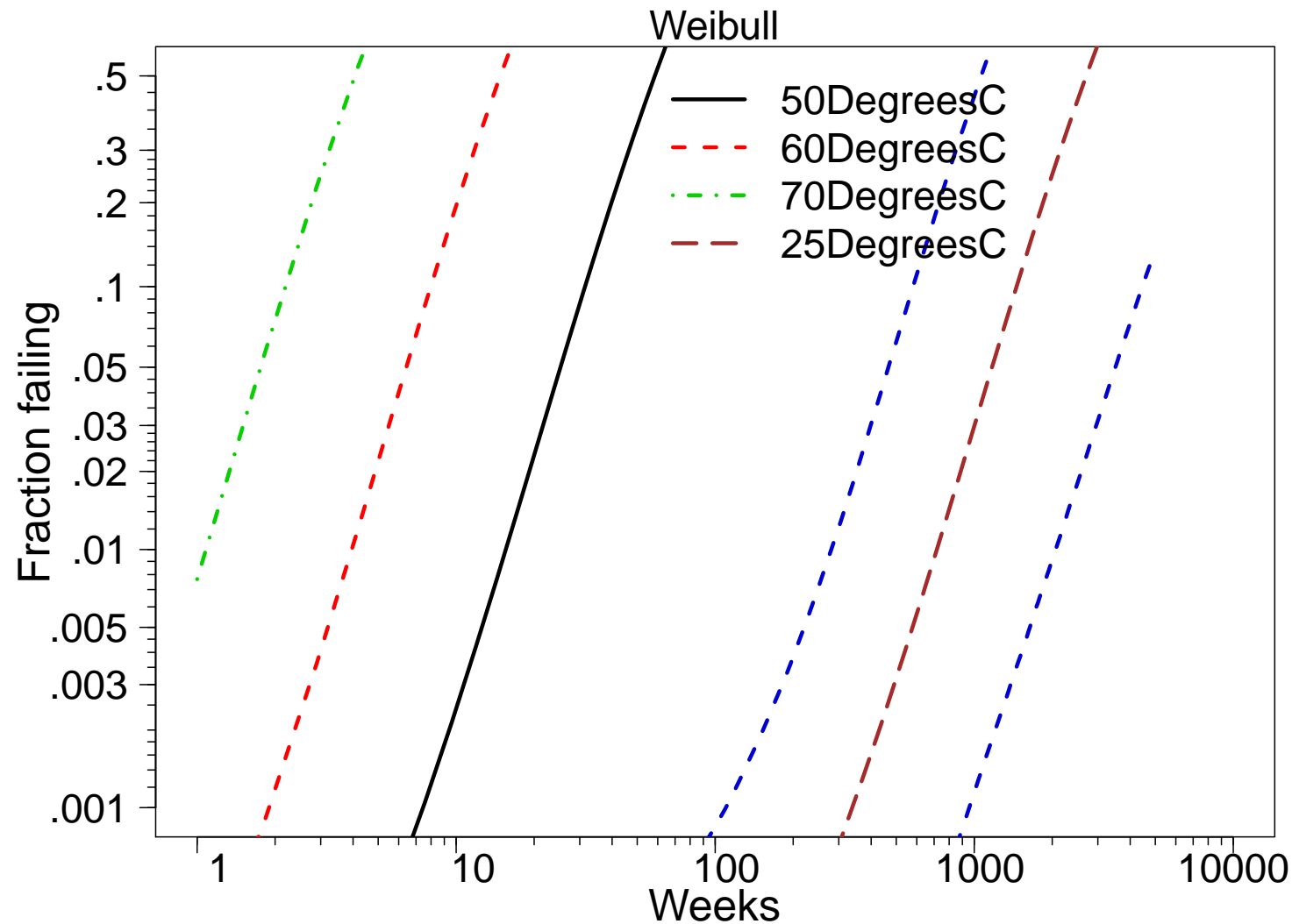
$$\hat{y}_p = \hat{\beta}_0 - \hat{\beta}_1^{[25]} \tau + \hat{\sigma} \Phi_{\text{norm}}^{-1}(p)$$



Adhesive Bond B

Weibull Multiple Probability Plot

cdf Estimates at Test Temperatures and Use Conditions



Quantiles for the Failure Time Distribution at Fixed Values of x and \mathcal{D}_f for Model 6

For Model 6, the p quantile is $t_p = h_t^{-1}(\tau_p)$, where

$$\tau_p = \begin{cases} 0 & \text{if } p \leq F(0, x) \\ \frac{1}{\beta_1 AF} [\beta_0 - h_d(\mathcal{D}_f) + \Phi^{-1}(p)\sigma] & \text{if } p > F(0, x), \end{cases}$$

where

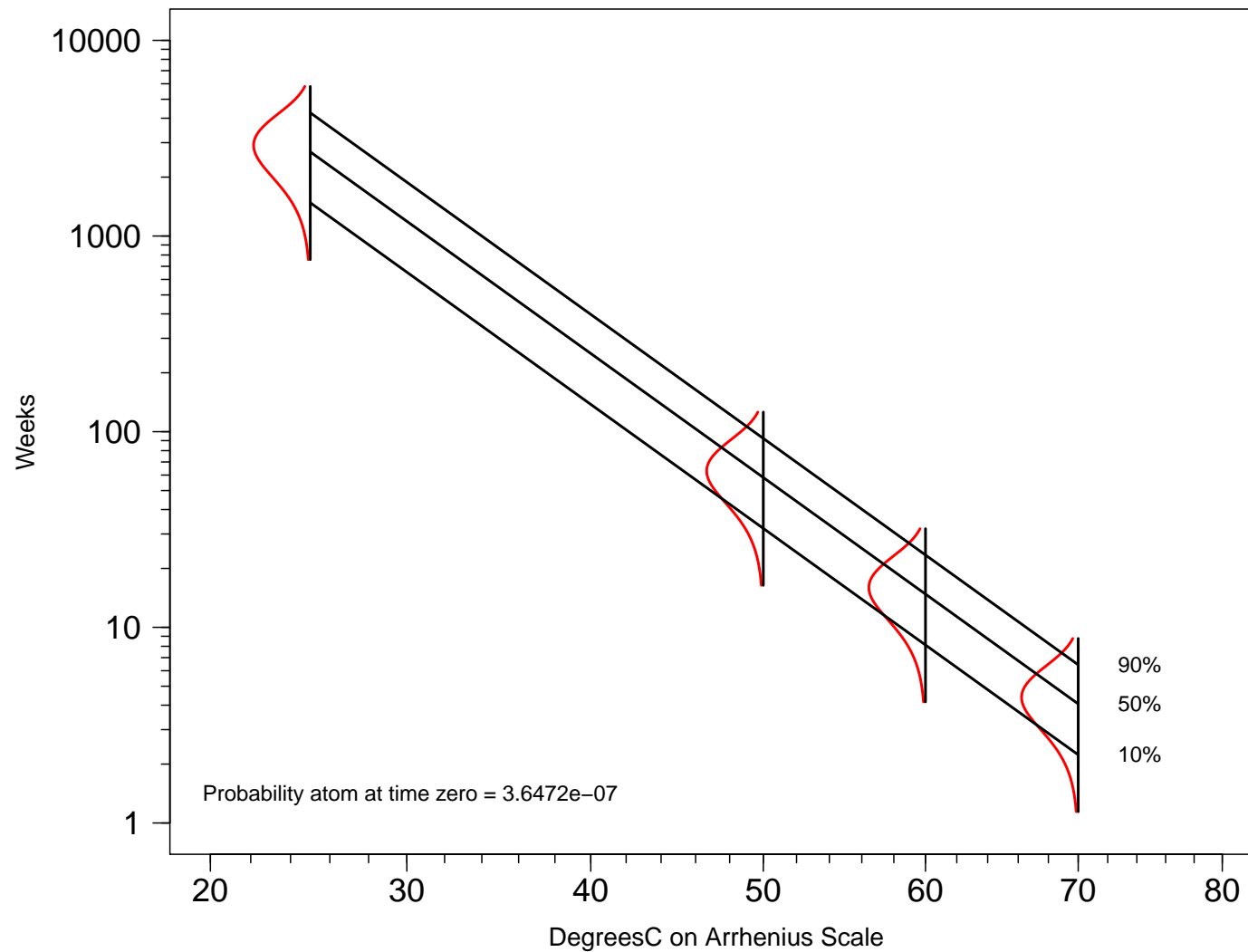
$$AF = \exp[-\beta_2(x - x_0)]$$

and

$$\begin{aligned} F(0, x) &= \Pr[Y \leq h_d(\mathcal{D}_f)] \\ &= \Phi \left[\frac{h_d(\mathcal{D}_f) - \beta_0}{\sigma} \right]. \end{aligned}$$

Adhesive Bond B Data

Model Plot Estimates of Failure-Time Distribution as a Function of Temperature



Chapter 20

Degradation Modeling and Destructive Degradation Data Analysis

Segment 9

ADDT with an Asymptotic Model Adhesive Formulation K

Accelerated Destructive Degradation Test of Adhesive Formulation K

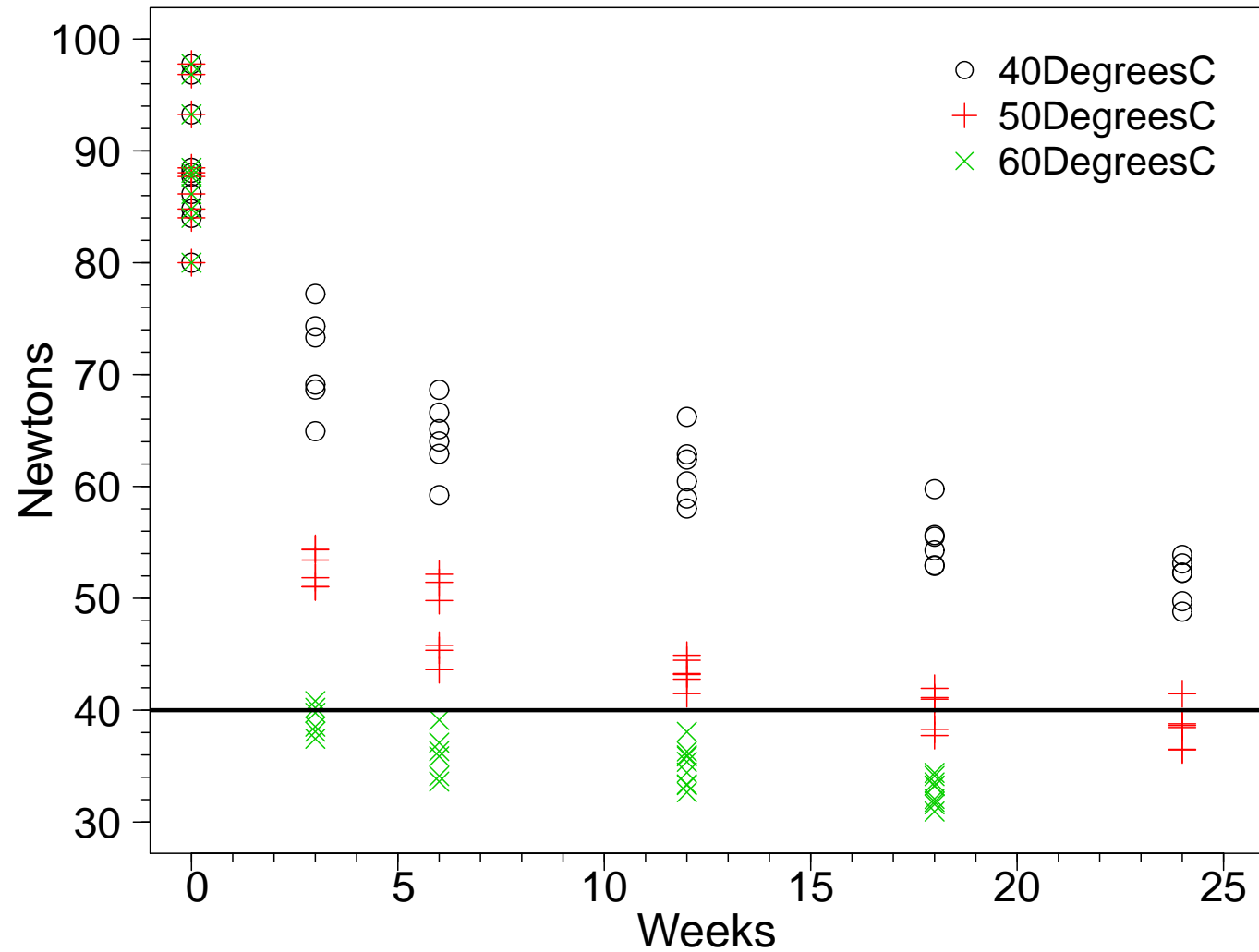
- Formulation K was a newly developed adhesive using a special additive compound that enhances performance.
- The additive degrades over time, through a diffusion process, reducing adhesive strength.
- **Objective:** Assess the strength of the adhesive as a function of time. Estimate the fraction of devices with a strength below 45 Newtons after 2 and 5 years of operation (approximately 104 and 260 weeks, respectively) at 25°C.
- 30 specimens were put into temperature-controlled chambers at 40, 50, and 60°C (total of 90 specimens).
- A specified number of units were removed and tested destructively after 3, 6, 12, 18 and 24 weeks of exposure.
- An additional 10 units with no aging were measured at the start of the experiment.

Adhesive Formulation K Test Plan

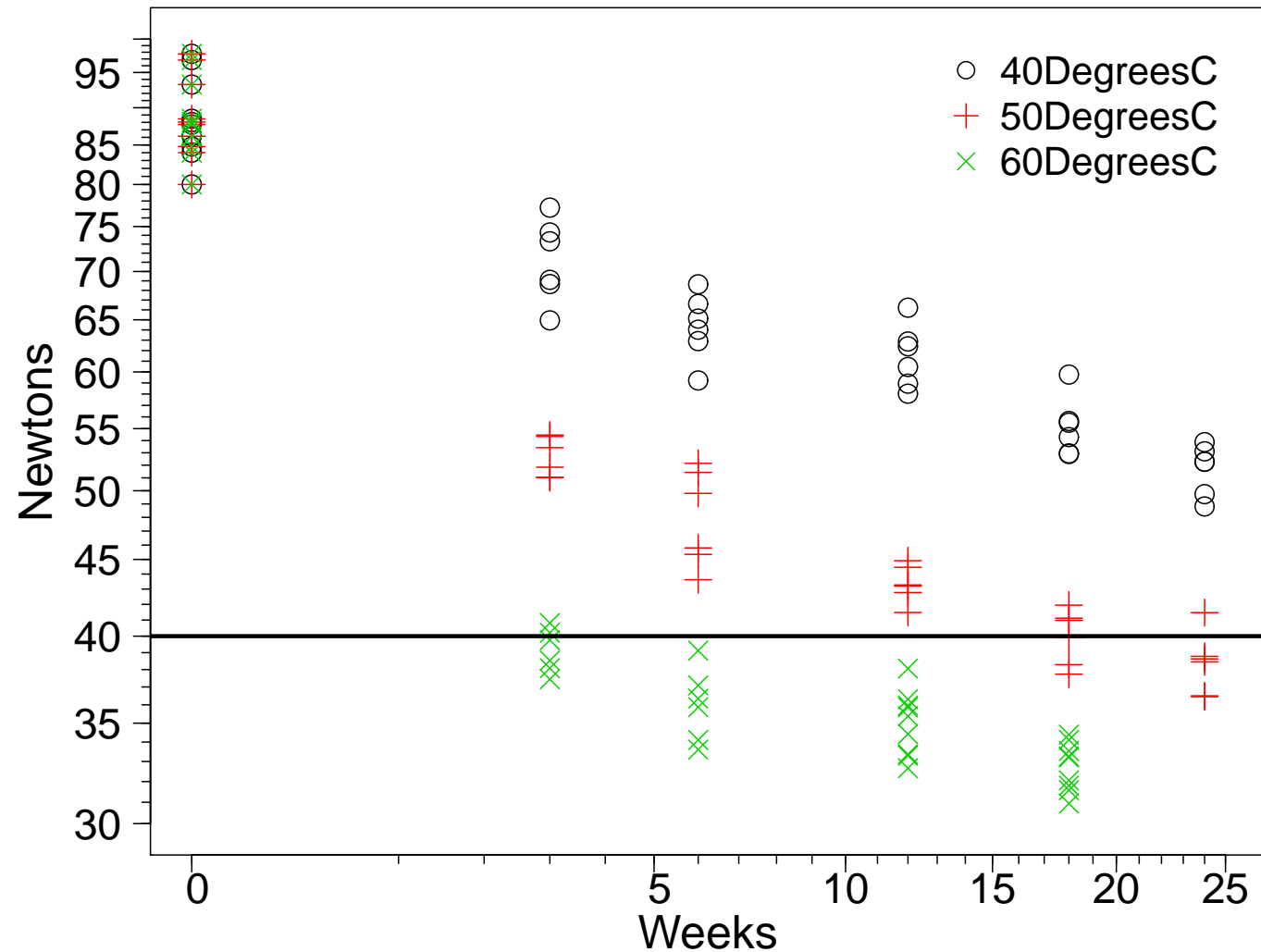
Number of Specimens Tested

Temp °C	Weeks Aged						Totals
	0	3	6	12	18	24	
—	10						10
40		6	6	6	6	6	30
50		6	6	6	6	6	30
60		6	6	9	9	0	30
Totals	10	18	18	21	21	12	106

Adhesive Formulation K ADDT Data as a Function of Temperature Linear-Linear Axes



Adhesive Formulation K ADDT Data as a Function of Temperature Square Root–Log Axes

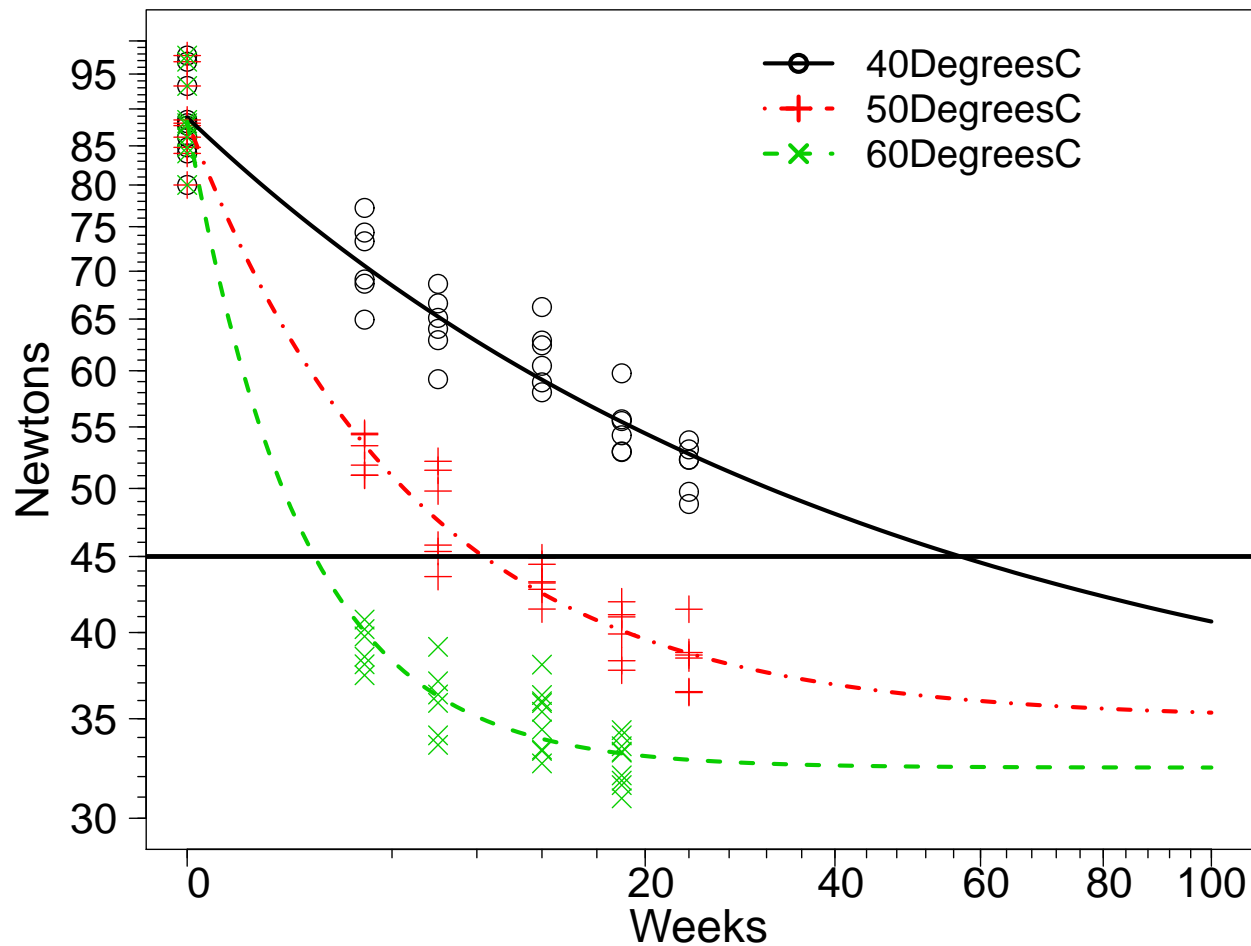


Adhesive Formulation K ADDT Data

Overlay of Individual Normal Distribution Fits

Square Root–Log Axes

$$\hat{\xi}^{[j]}(t) = \hat{\beta}_0^{[j]} - \hat{\beta}_3^{[j]}[1 - \exp(-\hat{\beta}_1^{[j]}\tau)], \quad j = 50, 60, 70$$



Adhesive Formulation K ADDT Data

Bayesian Parameter Estimates

Asymptotic Path Normal Distribution

Individual Line Fits

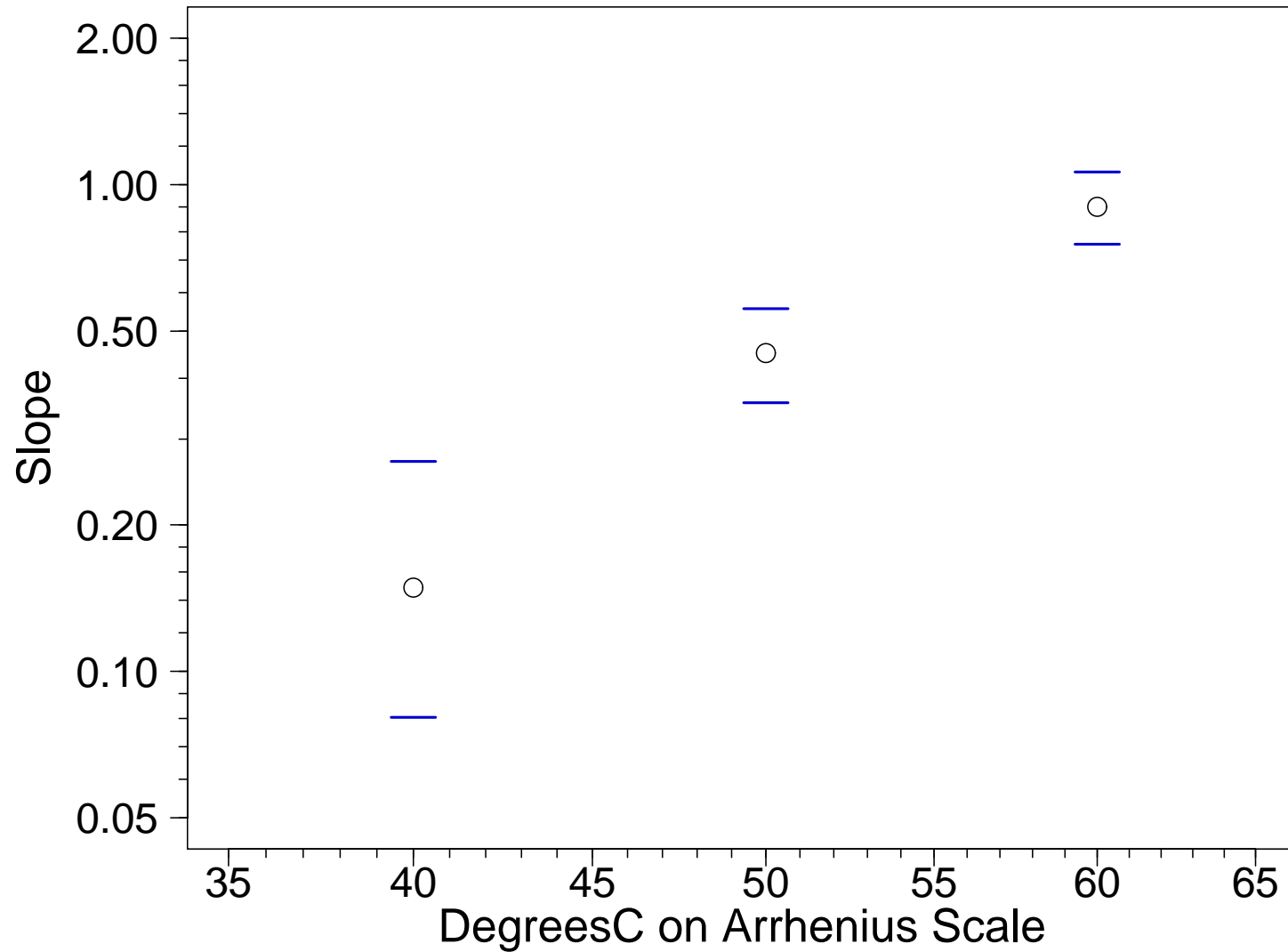
- For each temperature level three individual estimates are obtained: $\hat{\beta}_0^{[j]}$, $\hat{\beta}_1^{[j]}$, $\hat{\beta}_3^{[j]}$, and $\hat{\sigma}^{[j]}$.
- A summary of the asymptotic path normal distribution estimates for individual temperatures for the Adhesive Formulation K ADDT data is

Temperature	Estimates				95% Credible Interval for $\hat{\beta}_1^{[j]}$	
	$\hat{\beta}_0^{[j]}$	$\hat{\beta}_1^{[j]}$	$\hat{\beta}_3^{[j]}$	$\hat{\sigma}^{[j]}$	$\tilde{\beta}_1^{[j]}$	$\tilde{\beta}_1^{[j]}$
40°C	4.49	0.15	1.01	0.056	0.081	0.27
50°C	4.48	0.45	0.93	0.052	0.36	0.56
60°C	4.48	0.90	1.00	0.054	0.32	1.06

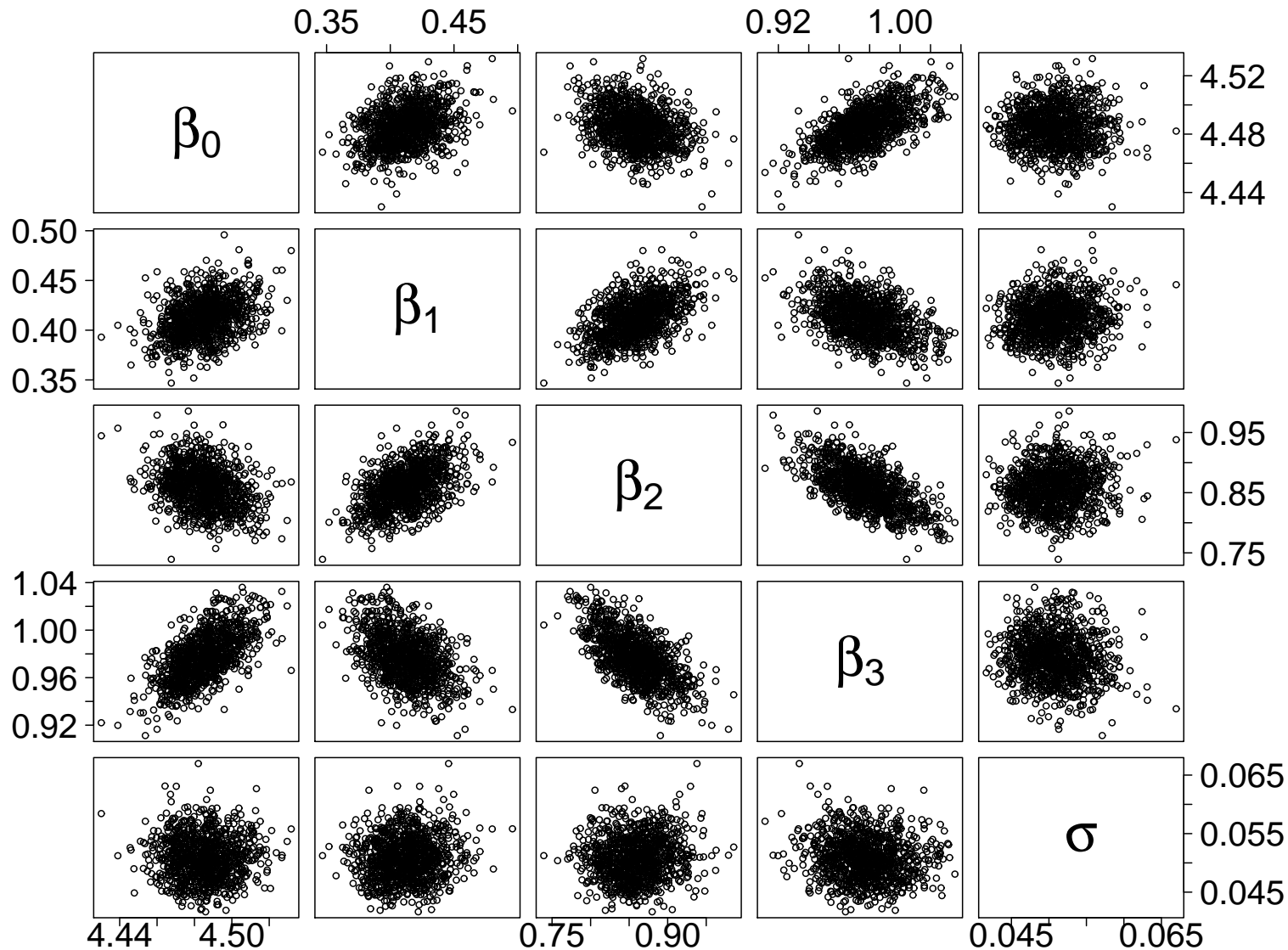
Adhesive Formulation K ADDT Data Arrhenius Plot

Individual Degradation Rate Estimates $\hat{\beta}_1^{[j]}$ versus °C

Arrhenius Plot



Adhesive Formulation K ADDT Data
Log/Square Root Transformation
Weakly Informative Prior Distribution
Posterior Pairs Plot



Adhesive Formulation K ADDT Data

Bayesian Parameter Estimates

Normal Distribution Asymptotic Path Arrhenius Model

$$Y = \beta_0 - \beta_3[1 - \exp(-\beta_1 \exp[-\beta_2(x - x_0)]\tau)] + \epsilon$$

Parameter	Estimate	Standard Error	95% Credible Interval	
			Lower	Upper
β_0	4.49	0.01	4.46	4.51
β_1	0.41	0.02	0.37	0.45
β_2	0.86	0.03	0.79	0.93
β_3	0.98	0.02	0.94	1.02
σ	0.05	0.005	0.04	0.06

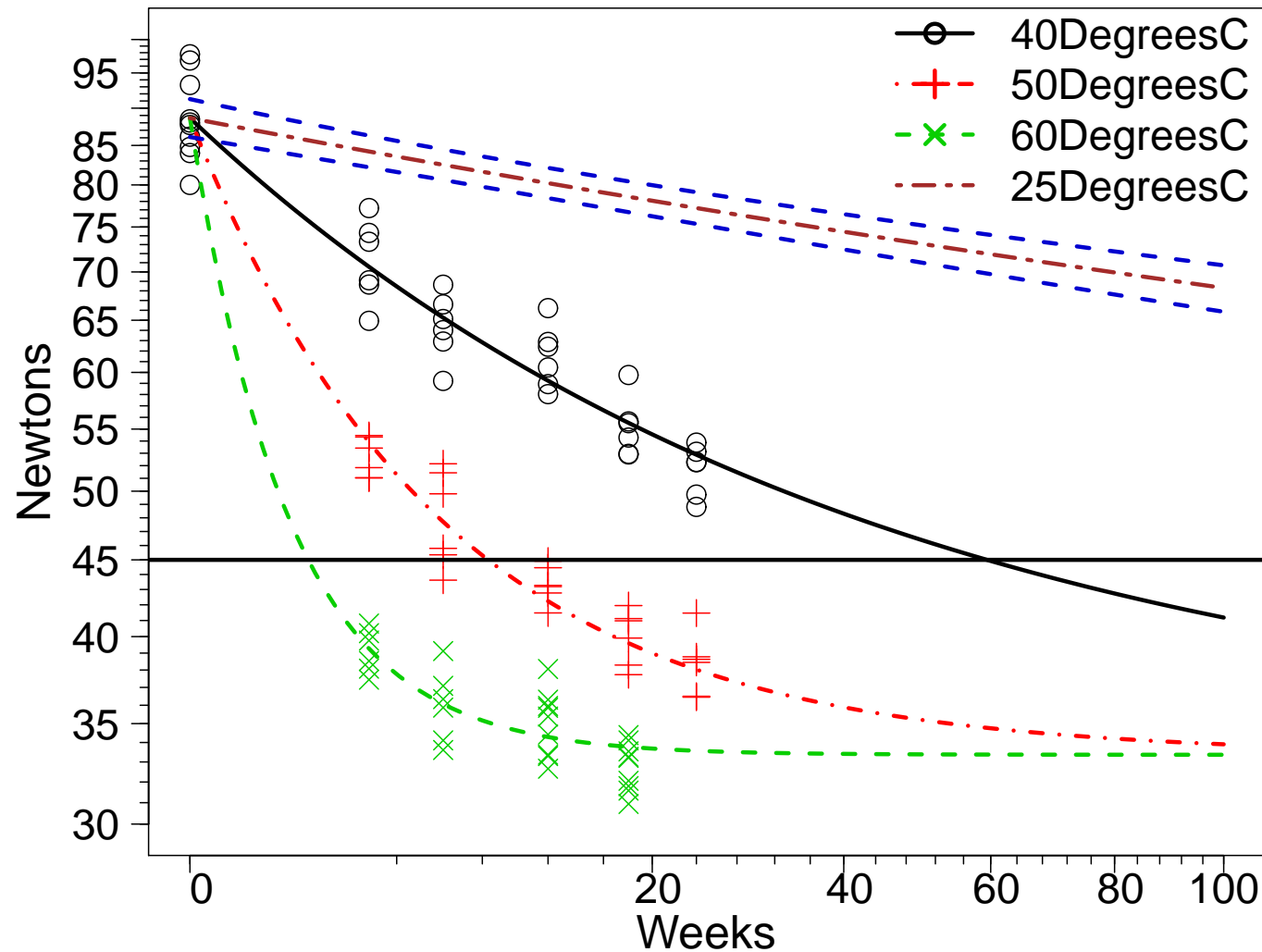
Estimates for the slopes (degradation rates) at each temperature are obtained from $\hat{\beta}_1^{[j]} = \hat{\beta}_1 \exp[-\hat{\beta}_2(x - x_0)]$ where $x = 11604.52/(\text{°C} + 273.15)$. In this case for the four temperatures of interest, the estimates are

$$\begin{aligned} \hat{\beta}_1^{[25]} &= 0.031, & \hat{\beta}_1^{[40]} &= 0.154 \\ \hat{\beta}_1^{[50]} &= 0.412, & \hat{\beta}_1^{[60]} &= 1.037 \end{aligned}$$

Adhesive Formulation K ADDT Data and Fitted Model

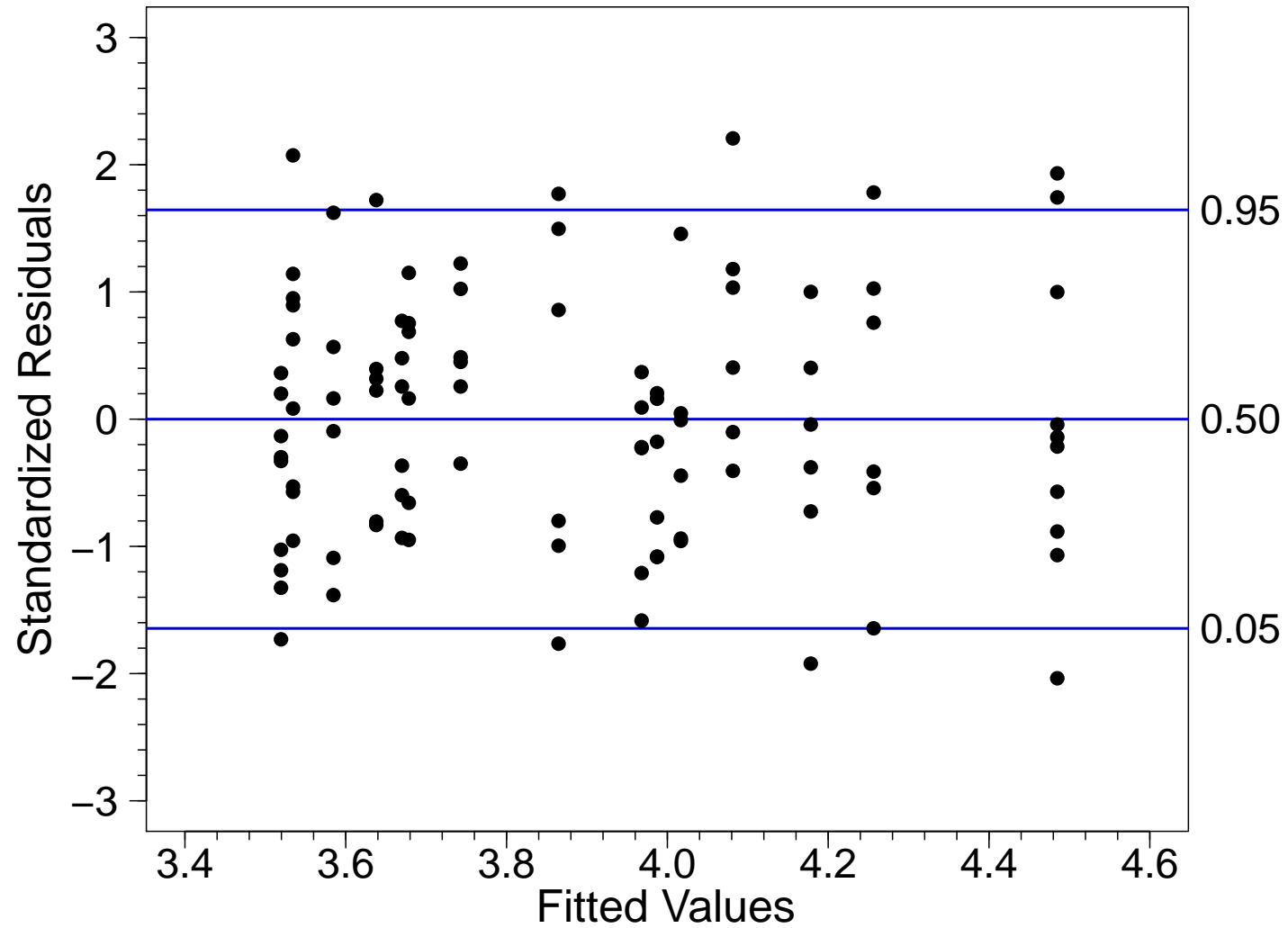
Normal Distribution Asymptotic Path Arrhenius Model

$$\hat{\xi}(t) = \hat{\beta}_0 - \hat{\beta}_3 \left[1 - \exp \left(-\hat{\beta}_1 \exp \left[-\hat{\beta}_2 (x - x_0) \right] \tau \right) \right]$$



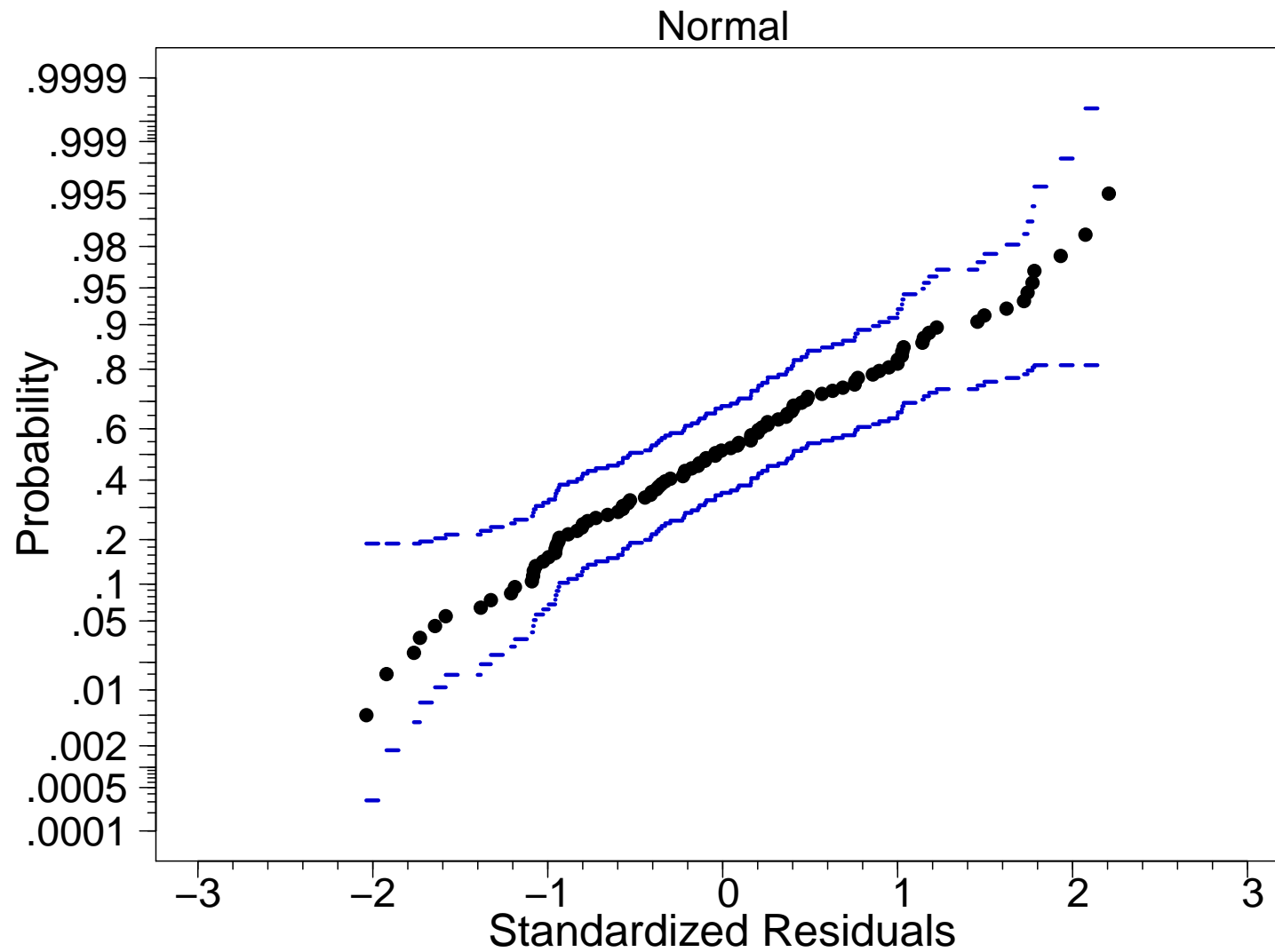
Adhesive Formulation K ADDT Data

Residuals Versus Fitted Values



Adhesive Formulation K ADDT Data

Normal Distribution Residual Probability Plot



Induced Failure Time Distribution for the Asymptotic Model 8 (Decreasing Degradation)

- For Model 8, $T \leq t$ is equivalent to observed degradation less than \mathcal{D}_f [i.e., $Y \leq h_d(\mathcal{D}_f)$]. Then

$$F(t, x) = \Pr[Y \leq h_d(\mathcal{D}_f)] = \Phi \left[\frac{h_d(\mathcal{D}_f) - \xi(t, x)}{\sigma} \right], \text{ for } t \geq 0.$$

- This failure time distribution is a mixed distribution with probability **atoms** at $t = 0$ and $t = \infty$ with probabilities

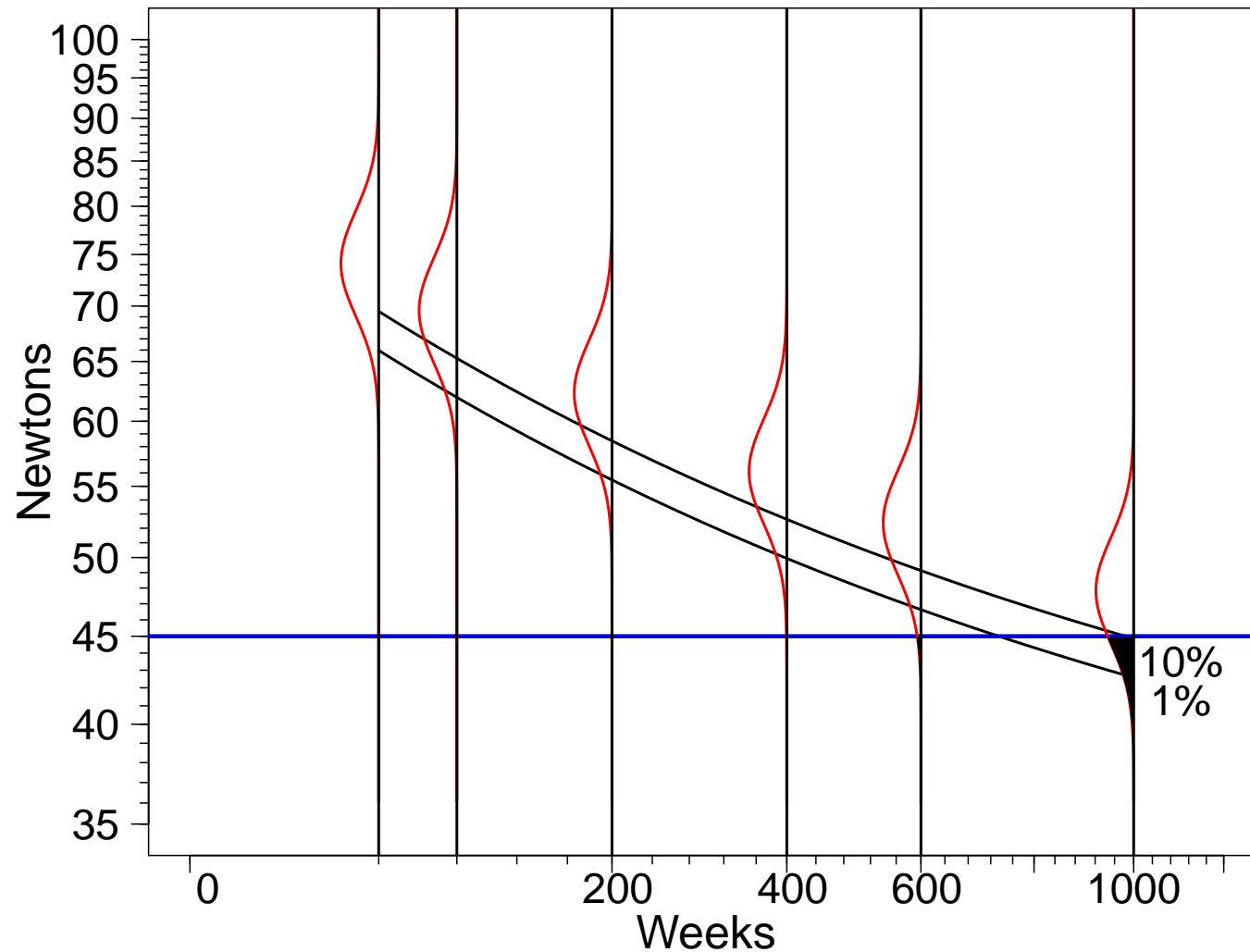
$$\Pr(T = 0, x) = F(0, x) = \Phi \left[\frac{h_d(\mathcal{D}_f) - \xi(0, x)}{\sigma} \right] = \Phi \left[\frac{h_d(\mathcal{D}_f) - \beta_0}{\sigma} \right]$$

$$\Pr(T = \infty, x) = 1 - F(\infty, x) = 1 - \Phi \left[\frac{h_d(\mathcal{D}_f) - (\beta_0 - \beta_3)}{\sigma} \right].$$

Adhesive Formulation K

Estimate of Fraction Failing as a Function of Time

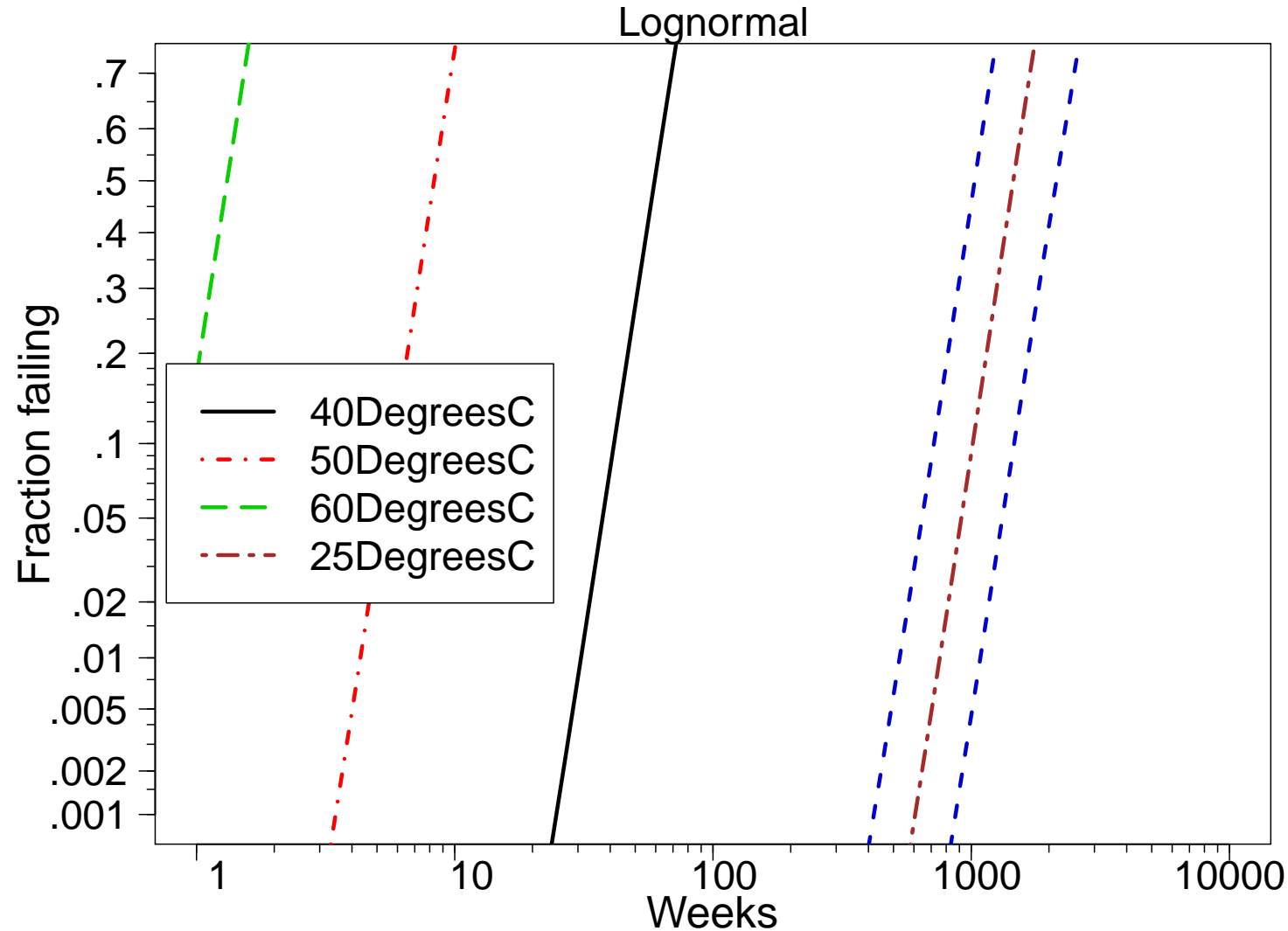
$$\hat{y}_p = \hat{\beta}_0 - \hat{\beta}_3 \left(1 - \exp \left\{ -\hat{\beta}_1^{[25]} \tau \right\} \right) + \hat{\sigma} \Phi_{\text{norm}}^{-1}(p)$$



Adhesive Formulation K

Lognormal Multiple Probability Plot

cdf Estimates at Test Temperatures and Use Conditions



Quantiles for the Failure Time Distribution at Fixed Values of x and \mathcal{D}_f for Model 8

- For Model 8, the p quantile is $t_p = h_t^{-1}(\tau_p)$, where

$$\tau_p = \begin{cases} 0 & \text{if } p \leq F(0, x) \\ \frac{1}{\beta_1 AF} \log \left[\frac{\beta_3}{h_d(\mathcal{D}_f) - \Phi^{-1}(p)\sigma - (\beta_0 - \beta_3)} \right] & \text{if } F(0, x) < p < F(\infty, x) \\ \infty & \text{if } p > F(\infty, x), \end{cases}$$

where

$$AF = \exp[-\beta_2(x - x_0)]$$

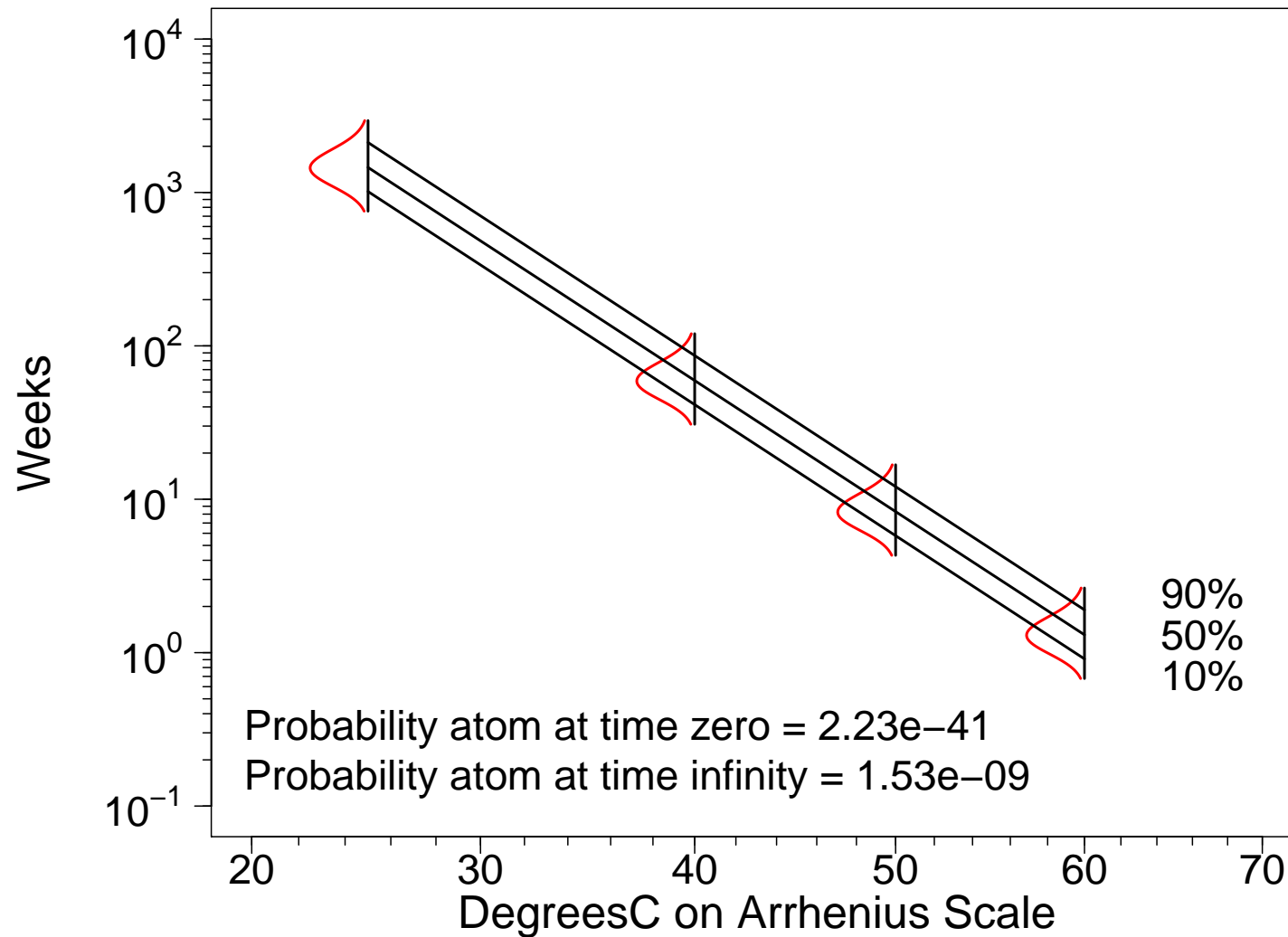
and

$$F(0, x) = \Phi \left[\frac{h_d(\mathcal{D}_f) - \beta_0}{\sigma} \right]$$

$$F(\infty, x) = \Phi \left[\frac{h_d(\mathcal{D}_f) - (\beta_0 - \beta_3)}{\sigma} \right].$$

Adhesive Formulation K

Model Plot Estimates of Failure Time Distribution as a Function of Temperature



References

Meeker, W. Q., L. A. Escobar, and F. G. Pascual (2021).
Statistical Methods for Reliability Data (Second Edition).
Wiley. [\[1\]](#)